R&S®RTP
High-Performance Oscilloscope
Specifications

ROHDE&SCHWARZ

Data Sheet | Version 05.00

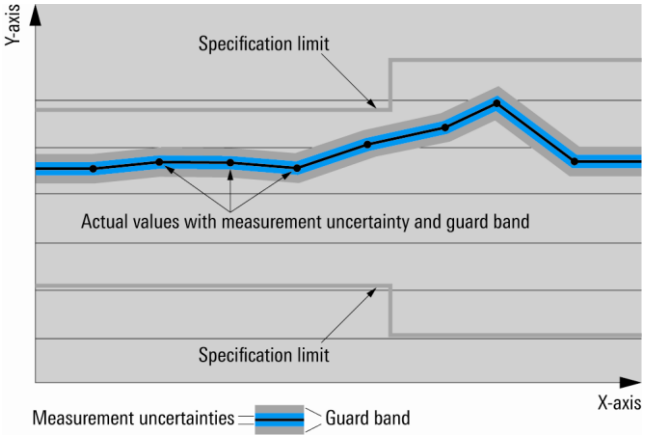
CONTENTS

Definitions

General
Product data applies under the following conditions:

- Three hours storage at ambient temperature followed by 30 minutes warm-up operation
- Specified environmental conditions met
- Recommended calibration interval adhered to
- All internal automatic adjustments performed, if applicable

Specifications with limits
Represent warranted product performance by means of a range of values for the specified parameter. These specifications are marked with limiting symbols such as <, ≤, >, ≥, ±, or descriptions such as maximum, limit of, minimum. Compliance is ensured by testing or is derived from the design. Test limits are narrowed by guard bands to take into account measurement uncertainties, drift and aging, if applicable.



Specifications without limits
Represent warranted product performance for the specified parameter. These specifications are not specially marked and represent values with no or negligible deviations from the given value (e.g. dimensions or resolution of a setting parameter). Compliance is ensured by design.

Typical data (typ.)
Characterizes product performance by means of representative information for the given parameter. When marked with <, > or as a range, it represents the performance met by approximately 80 % of the instruments at production time. Otherwise, it represents the mean value.

Nominal values (nom.)
Characterize product performance by means of a representative value for the given parameter (e.g. nominal impedance). In contrast to typical data, a statistical evaluation does not take place and the parameter is not tested during production.

Measured values (meas.)
Characterize expected product performance by means of measurement results gained from individual samples.

Uncertainties
Represent limits of measurement uncertainty for a given measurand. Uncertainty is defined with a coverage factor of 2 and has been calculated in line with the rules of the Guide to the Expression of Uncertainty in Measurement (GUM), taking into account environmental conditions, aging, wear and tear.

Device settings and GUI parameters are indicated as follows: “parameter: value”.

Typical data as well as nominal and measured values are not warranted by Rohde & Schwarz.

In line with the 3GPP/3GPP2 standard, chip rates are specified in Mcps (million chips per second), whereas bit rates and symbol rates are specified in Mbps (million bits per second), kbps (thousand bits per second), Msps (million symbols per second) or ksps (thousand symbols per second), and sample rates are specified in Msample/s (million samples per second). Mcps, Mbps, Msps, kbps, ksps and Msample/s are not SI units.

Base unit

Vertical system

Input channels		4 channels	
Input impedance	offset and position set to zero	50 Ω ± 2 %	
Analog bandwidth (–3 dB)	R&S®RTP044	≥ 4 GHz	
	R&S®RTP064	≥ 6 GHz	
	R&S®RTP084	≥ 8 GHz	
Rise time/fall time	10 % to 90 %, calculated from 0.43/analog bandwidth		
	R&S®RTP044	108 ps	
	R&S®RTP064	72 ps	
	R&S®RTP084	54 ps	
Input VSWR	input frequency		
	≤ 4 GHz	1.25 (meas.)	
	> 4 GHz to ≤ 8 GHz	1.4 (meas.)	
Vertical resolution		8 bit, 16 bit for high resolution decimation (with reduction of the sampling rate), 16 bit for high definition mode (without reduction of the sampling rate [1], requires R&S®RTP-K17 option)	
DC gain accuracy	offset and position set to zero		
	> 5 mV/div	±1.5 %	
	≤ 5 mV/div	±2 %	
Input coupling		DC, GND	
Input sensitivity	entire analog bandwidth supported for all input sensitivities; digital zoom at sensitivities < 2 mV/div	1 mV/div to 1 V/div	
Maximum input voltage		±5 V	
Position range		±5 div	
Offset range	input sensitivity		
	> 100 mV/div	±5 V	
	≤ 100 mV/div	±(1.5 V – input sensitivity × 5 div)	
Offset accuracy	input sensitivity		
	> 100 mV/div	±(0.35 % × |net offset| + 0.1 div × input sensitivity)	
	≤ 100 mV/div, net offset ≤ 1 V	±(0.35 % × |net offset| + 0.1 div × input sensitivity + 2 mV)	
	≤ 100 mV/div, net offset > 1 V	±1 % × |net offset|	
	net offset = offset – position × input sensitivity		
DC measurement accuracy	after adequate suppression of measurement noise	±(DC gain accuracy × |reading – net offset| + offset accuracy)	
Channel-to-channel isolation (each channel at 100 mV/div)	between channels 1-3, 1-4, 2-3, 2-4	> 60 dB (meas.)	
	between channels 1-2 and 3-4	> 40 dB (meas.)	
RMS noise floor (meas.) (corresponding signal to noise ratio at full scale (calculated))	input sensitivity	R&S®RTP044	R&S®RTP064
	1 mV/div	270 µV (22.3 dB)	340 µV (20.3 dB)
	2 mV/div	270 µV (28.3 dB)	340 µV (26.3 dB)
	5 mV/div	280 µV (36.0 dB)	360 µV (33.8 dB)
	10 mV/div	410 µV (38.7 dB)	500 µV (37.0 dB)
	20 mV/div	630 µV (41.0 dB)	750 µV (39.5 dB)
	50 mV/div	1.4 mV (42.0 dB)	1.7 mV (40.3 dB)
	100 mV/div	2.7 mV (42.3 dB)	3.1 mV (41.1 dB)
	200 mV/div	6.6 mV (40.6 dB)	8.2 mV (38.7 dB)
	500 mV/div	14 mV (42.0 dB)	17 mV (40.3 dB)
	1 V/div	27 mV (42.3 dB)	32 mV (40.9 dB)
	input sensitivity	R&S®RTP084	
	1 mV/div	430 µV (18.3 dB)	
	2 mV/div	430 µV (24.3 dB)	
	5 mV/div	440 µV (32.1 dB)	
	10 mV/div	620 µV (35.1 dB)	
	20 mV/div	880 µV (38.1 dB)	
	50 mV/div	2.0 mV (38.9 dB)	

[1] The maximum realtime sampling rate of the R&S®RTP-K17 option is 10 Gsample/s.

	100 mV/div	3.6 mV (39.8 dB)
	200 mV/div	9.8 mV (37.2 dB)
	500 mV/div	21 mV (38.5 dB)
	1 V/div	36 mV (39.8 dB)

Horizontal system

Timebase range		selectable between 20 ps/div and 10 000 s/div, time per div settable to any value within range
Channel deskew		±100 ns
Reference position		10 % to 90 % of measurement display area
Trigger offset range	max.	+(memory depth/current sampling rate)
	min.	–10 000 s
Modes		normal, roll
Channel-to-channel skew		< 100 ps (meas.)
Timebase accuracy	after delivery/calibration, at +23 °C	±10 ppb
	during calibration interval	±100 ppb
	long-term stability (more than one year since calibration)	±(50 + 50 × years since calibration) ppb
Sample clock jitter	acquired time range	RMS value (meas.)
	1 µs	50 fs
	10 µs	63 fs
	100 µs	72 fs
	1 ms	76 fs
	10 ms	124 fs
Intrinsic jitter	RMS value	200 fs (meas.)
Time interval error (TIE)	RMS values	$\sqrt{(\text{Noise/SlewRate})^2 + (\text{Intrinsic Jitter})^2}$
Periodic jitter	RMS values	$\sqrt{2}\sqrt{(\text{Noise/SlewRate})^2 + (\text{Intrinsic Jitter})^2}$
Cycle-to-cycle jitter	RMS values	$\sqrt{3}\sqrt{(\text{Noise/SlewRate})^2 + (\text{Intrinsic Jitter})^2}$

Acquisition system

Realtime sampling rate		max. 20 Gsample/s on each channel
Realtime waveform acquisition rate	max.	> 950 000 waveforms/s
Memory depth [2]	standard	50 Msample on 4 channels
		100 Msample on 2 channels
		200 Msample on 1 channel
	R&S®RTP-B101 option	100 Msample on 4 channels
		200 Msample on 2 channels
		400 Msample on 1 channel
	R&S®RTP-B102 option	200 Msample on 4 channels
		400 Msample on 2 channels
		800 Msample on 1 channel
	R&S®RTP-B105 option	500 Msample on 4 channels
		1 Gsample on 2 channels
		2 Gsample on 1 channel
	R&S®RTP-B110 option	1 Gsample on 4 channels
		2 Gsample on 2 channels
Realtime digital filters	selectable for the data acquisition and/or the trigger system	
	lowpass for acquisition system	cutoff frequency selectable from 100 kHz to 500 MHz
	lowpass for acquisition and trigger system	cutoff frequency selectable from 1 GHz to the analog bandwidth with fine granularity
Decimation modes	sample	first sample in decimation interval
	peak detect	largest and smallest sample in decimation interval
	high resolution	average value of samples in decimation interval
	root mean square	root of squared average of samples in decimation interval

[2] The maximum available memory depth depends on the bit depth of the acquired data and, therefore, on the settings of the acquisition system, such as decimation mode, waveform arithmetic, number of waveform streams and high definition mode.

Waveform arithmetic	off	no arithmetic
	envelope	envelope of acquired waveforms
	average	average of acquired waveforms, max. average depth depends on decimation mode [3]
	sample	max. 16 777 215
	high resolution	max. 65 535
	root mean square	max. 255
	reset condition	no reset (standard), reset by time, reset by number of processed waveforms
Waveform streams per channel		up to 3 with independent selection of decimation mode and waveform arithmetic
Sampling modes	realtime mode	max. sampling rate set by digitizer
	interpolated time	enhancement of sampling resolution by interpolation; max. equivalent sampling rate is 5 Tsample/s
Interpolation modes		linear, sin(x)/x, sample&hold
Ultra-segmented mode	continuous recording of waveforms in acquisition memory without interruption due to visualization	
	max. realtime waveform acquisition rate	> 3 200 000 waveforms/s
	min. blind time between consecutive acquisitions	< 310 ns

Trigger system

Sources		channel 1, channel 2, channel 3, channel 4, inverted channels, external trigger, line trigger
Sensitivity	trigger hysteresis mode	auto (standard) or manual
	range	0 V to 5 div × input sensitivity
Trigger jitter	full-scale sine wave of frequency set to –3 dB bandwidth	< 1 ps (RMS) (meas.)
Coupling mode	standard	same as selected channel
	lowpass filter	cutoff frequency selectable from 1 GHz to analog bandwidth
Sweep mode		auto, normal, single, n single
Event rate	max.	one event for every 200 ps time interval
Trigger level	range	±5 div from center of screen
Holdoff range	time	100 ns to 10 s, fixed and random
	events	1 event to 2 000 000 000 events

Main trigger modes		
Edge	triggers on specified slope (positive, negative or either) and level	
Glitch	triggers on glitches of positive, negative or either polarity that are shorter or longer than specified width	
	glitch width	50 ps to 10 000 s
Width	triggers on positive or negative pulse of specified width; width can be shorter, longer, inside or outside the interval	
	pulse width	50 ps to 10 000 s
Runt	triggers on pulse of positive, negative or either polarity that crosses one threshold but fails to cross a second threshold before crossing the first one again; runt pulse width can be arbitrary, shorter, longer, inside or outside the interval	
	runt pulse width	50 ps to 10 000 s
Window	triggers when signal enters or exits a specified voltage range; triggers also when signal stays inside or outside the voltage range for a specified period of time	
Timeout	triggers when signal stays high, low or unchanged for a specified period of time	
	timeout	50 ps to 10 000 s
Interval	triggers when time between two consecutive edges of same slope (positive or negative) is shorter, longer, inside or outside a specified range	
	interval time	50 ps to 10 000 s

[3] Waveform averaging is not compatible with peak detect decimation.

Slew rate	triggers when the time required by a signal edge to toggle between user-defined upper and lower voltage levels is shorter, longer, inside or outside the interval; edge slope may be positive, negative or either	
	toggle time	50 ps to 10 000 s
Data2clock	triggers on setup time and hold time violations between clock and data present on any two input channels; monitored time interval may be specified by the user in the range from –100 ns to 100 ns around a clock edge and must be at least 100 ps wide	
Pattern	triggers when a logical combination (and, nand, or, nor) of the input channels stays true for a period of time shorter, longer, inside or outside a specified range	
State	triggers when a logical combination (and, nand, or, nor) of the input channels stays true at a slope (positive, negative or either) in one selected channel	

Advanced trigger modes		
Trigger qualification	trigger events may be qualified by a logical combination of unused channels	
	qualifiable events	edge, glitch, width, runt, window, timeout, interval
Sequence trigger (A/B/R trigger)	triggers on B event after occurrence of A event; delay condition after A event specified either as time interval or number of B events; an optional R event resets the trigger sequence to A	
	A event	any trigger mode
	B event	edge, glitch, width, runt, window, timeout, interval, slew rate
	R event	edge, glitch, width, runt, window, timeout, interval, slew rate
Zone trigger		with R&S®RTP-K19 option
External trigger input	input impedance	50 Ω (nom.)
	max. input voltage	5 V (RMS)
	trigger level range	±5 V
	sensitivity, for input frequency ≤ 500 MHz	300 mV (peak-to-peak)
	input coupling	50 Ω, GND, HF reject (attenuates > 50 kHz), LF reject (attenuates < 50 kHz)
	trigger modes	edge (rise or fall)
Trigger out	functionality	a pulse is generated for every acquisition trigger event
	output voltage	0 V to 5 V at high impedance
		0 V to 2.5 V at 50 Ω
	pulse width	selectable between 4 ns and 60 ms
	pulse polarity	low active or high active
	output delay	depends on trigger settings
	jitter	±600 ps (meas.)

Waveform measurements

General features	measurement panels	up to 8 measurement panels; each panel may contain any number of automatic measurements of the same category
	gate	delimits the display region evaluated for automatic measurements
	reference levels	user-configurable vertical levels define support structures for automatic measurements
	statistics	displays maximum, minimum, mean, standard deviation, RMS and measurement count for each automatic measurement
	track	measurement results displayed as continuous trace that is time-correlated to the measurement source
	long-term analysis	history of selected measurements as trace against count index
	histogram	available for the main measurement of each measurement panel; automatic or manual selection of bin number and scale; counters for measurements under, within and over the histogram range
	limit check	measurements tested against user-defined margins and limits; pass or fail conditions may launch automatic response: acquisition stop, beep, print and save waveform
Measurement category	amplitude and time	amplitude, high, low, maximum, minimum, peak-to-peak, mean, RMS, sigma, overshoot, area, rise time, fall time, positive width, negative width, period, frequency, duty cycle, delay, phase, burst width, pulse count, positive switching, negative switching, cycle area, cycle mean, cycle RMS, cycle sigma, setup/hold time, setup/hold ratio, pulse train, slew rate rising, slew rate falling, DC voltmeter (requires Rohde & Schwarz active probe with R&S®ProbeMeter functionality)
	eye diagram	extinction ratio, eye height, eye width, eye top, eye base, Q factor, S/N ratio, duty cycle distortion, eye rise time, eye fall time, eye bit rate, eye amplitude, jitter (peak-to-peak, 6-sigma, RMS)
	spectrum	channel power, bandwidth, occupied bandwidth, harmonic search, total harmonic distortion THD in dB and % using power values, total harmonic distortion variants THD_a, THD_u and THD_r using voltage, overall voltage and overall voltage root means square, peak list (THD_a, THD_u, THD_r and peak list require R&S®RTP-K37 option)
	jitter	cycle-to-cycle jitter, N-cycle jitter, cycle-to-cycle width, cycle-to-cycle duty cycle, time-interval error, data rate, unit interval, skew delay, skew phase; requires R&S®RTP-K12 option

Cursors	setup	up to 4 cursor sets on screen, each set consisting of two horizontal and two vertical cursors
	target	acquired waveforms (input channels), math waveforms, reference waveforms, track waveforms, XY diagrams
	operating mode	vertical measurements, horizontal measurements or both; vertical cursors either set manually or locked to waveform
Histogram	source	acquired waveform (input channels), math waveform, reference waveform
	mode	vertical (for timing statistics), horizontal (for amplitude statistics)
	automatic measurements	waveform count, waveform samples, histogram samples, histogram peak, peak value, maximum, minimum, median, range, mean, sigma, mean ± 1, 2 and 3 sigma, marker ± probability

Mask testing

Test definition	number of masks	up to 8 simultaneously
	source	acquired waveforms (input channels), math waveforms
	fail condition	sample hit or waveform hit
	fail tolerance	minimum number of fail events for test fail in range from 0 to 4 000 000 000
	test rate	up to 600 000 waveforms/s
	action on error	acquisition stop, beep, print and save waveform
	save/load to file	test and mask settings (.xml format)
Mask definition with segments	number of independent segments	up to 8
	segment definition	array of points and connecting rule (upper, lower, inner) define segment region
	segment input	point and click on touchscreen, editable list
Mask definition with tolerance tube	input signal	acquired waveform
	definition of tolerance tube	horizontal width, vertical width, vertical stretch, vertical position
Mask definition with eye mask assistant (requires R&S®RTP-K12 option)	primary mask shape	
	type	diamond, square, hexagon, octagon
	dimensions	main and secondary height, main and secondary width, depending on selected shape
	position	vertical offset, horizontal offset
	secondary mask shapes	
	locations	any combination of left, right, top, bottom
	position	horizontal and vertical offset with respect to center of primary mask shape
Result statistics	category	completed acquisitions, remaining acquisitions, state, sample hits, mask hits, fail rate, test result (pass or fail)
Visualization options	waveform style	vectors, dots
	violation highlighting	hits (on/off), highlight persistence (50 ms to 50 s or infinite), waveform color (default: red)
	mask colors	configurable colors for mask without violation (default: translucent gray), mask with violation (default: translucent red), mask with contact (default: translucent pale red)

Waveform math

General features	number of math waveforms	up to 4
	number of reference waveforms	up to 4
	waveform arithmetic	user-selectable average or envelope of consecutive waveforms
Algebraic expressions	user may define complex mathematical expressions involving waveforms and measurement results	
	math functions	add, subtract, multiply, divide, absolute value, square, square root, integrate, differentiate, exp, $\log_{10}$, $\log_e$, $\log_2$, rescale, sin, cos, tan, arcsin, arccos, arctan, sinh, cosh, tanh, autocorrelation, crosscorrelation
	logical operators	not, and, nand, or, nor, xor, nxor
	relational operators	Boolean result of =, ≠, >, <, ≤, ≥
	frequency domain	spectral magnitude and phase, real and imaginary spectra, group delay
	digital filter	lowpass, highpass
	special functions	CDR transform; requires R&S®RTP-K12 option
Optimized math	operators	add, subtract, multiply, invert, absolute value, differentiate, $\log_{10}$, $\log_e$, $\log_2$, rescale, FIR, FFT magnitude
Spectrum analysis	FFT magnitude spectrum	
	setup parameters	center frequency, frequency span, frame overlap, frame window (rectangular, Hamming, Hann, Blackman, Gaussian, Flattop, Kaiser Bessel), user-selectable spectrum averaging, RMS, envelope, max. hold and min. hold (max. hold and min. hold require R&S®RTP-K37 option)
	max. realtime waveform acquisition rate	> 1 000 waveforms/s

Search and mark function

General description	scans acquired waveforms for occurrence of a user-defined set of events and highlights each occurrence	
Basic setup	source	all physical input channels, math waveforms, reference waveforms
	search panels	up to 8, where each panel may manage multiple event searches
	search mode	manually triggered or continuous
	search conditions	
	supported events	edge, glitch, width, runt, window, timeout, interval, slew rate, data2clock, state
	event configuration	identical to corresponding trigger event
	event selection	single or multiple events on same source
Search scope	mode	current waveform, gated time interval
Result visualization	table	
	sort mode	horizontal position or vertical value
	max. result count	specifies max. table size
	zoom window	centered on highlighted event

Display characteristics

Diagram types	Yt, XY, spectrum, long-term measurement, spectrogram (spectrogram requires R&S®RTP-K37 option)
Horizontal divisions	10
Vertical divisions	10
Display interface configuration	display area can be split up into separate diagram areas by dragging and dropping signal icons; each diagram area can hold any number of signals; diagram areas may be stacked on top of each other and later accessed via the dynamic tab menu
Signal bar	accommodates timebase settings, trigger settings and signal icons; signal bar may be docked to left or right side of display area or hidden
Signal icon	each active waveform is represented by a separate signal icon on the signal bar; the signal icon displays the individual vertical and acquisition settings; a waveform can be minimized to its signal icon so that it appears as a realtime preview in miniature form; dialog boxes and measurement results may also be minimized to a signal icon
Axis label	X-axis ticks and Y-axis ticks labeled with tick value and physical unit
Diagram label	diagrams may be individually labeled with a descriptive user-defined name
Diagram layout	grid, crosshair, axis labels and diagram label may be switched on and off separately
Persistence	50 ms to 50 s, or infinite
Zoom	user-defined zoom window provides vertical and horizontal zoom; each diagram area supports multiple zoom windows; touchscreen interface simplifies resize and drag operations on zoom window
Signal colors	predefined or user-defined color tables for persistence display

Input and output

Front		
Channel inputs		BNC-compatible, for details see Vertical system
	probe interface	auto-detection of passive probes, Rohde & Schwarz active probe interface
External trigger input		BNC, for details see Trigger system
	probe interface	auto-detection of passive probes, Rohde & Schwarz active probe interface
Probe compensation output	signal shape	rectangle, V_{low} = 0 V, V_{high} = 1 V amplitude 1 V (V_{pp}) ± 5 %
	frequency	1 kHz ± 1 %
	impedance	nom. 50 Ω
Ground jack		4 mm, connected to ground
USB interface		2 ports, type A plug, version 3.1 gen 1
Option slots		2

Rear		
Trigger out		BNC, for details see Trigger system
USB interface		2 ports, type A plug version 3.1 gen 1
		2 ports, type A plug version 2.0
		1 port, type B plug, version 3.1 gen 1
LAN interface		RJ-45 connector, supports 10/100/1000BASE-T
External monitor interface		DVI-D and display port, output of scope display or extended desktop display
GPIB interface	function	interface in line with IEC 625-2 (IEEE 488.2)
	command set	SCPI 1999.0
	connector	IEEE-488 24-pin Amphenol female
	interface functions	SH1, AH1, T6, L4, SR1, RL1, PP1, DC1, DT1, C0
External reference input	connector	BNC female
	impedance	nom. 50 Ω
	input frequency range	1 MHz to 20 MHz, in 1 MHz steps
	sensitivity	≥ 0 dBm into 50 Ω
Reference output 10 MHz	connector	BNC female
	impedance	nom. 50 Ω
	level	> 7 dBm
Auxiliary output		SMA connector, for future use
Digital Data Interface 40G		QSFP+ connector, for future use
Option slots		2
Security slot		for standard Kensington style lock

General data

Display	type	12.1" LC TFT color display with capacitive touchscreen
	resolution	1280 × 800 pixel (WXGA)

Temperature		
Temperature loading	operating temperature range	+5 °C to +45 °C
	storage temperature range	–40 °C to +70 °C
Temperature loading		in line with MIL-PRF-28800F section 4.5.5.1.1.1 class 3 for operation
Climatic loading		+25° C/+40 °C at 85 % rel. humidity cyclic, in line with IEC 60068-2-30
		+30 °C/+40 °C/+45 °C at 95/75/45 %, in line with MIL-PRF-28800F section 4.5.5.1.1.2 class 3 for operation

Altitude		
Operating		up to 3000 m above sea level
Nonoperating		up to 15000 m above sea level

Mechanical resistance		
Vibration	sinusoidal	5 Hz to 150 Hz, max. 1.8 g at 55 Hz, 0.5 g from 55 Hz to 150 Hz, in line with EN 60068-2-6
	random	10 Hz to 300 Hz, acceleration 1.2 g (RMS), in line with EN 60068-2-64
Shock		40 g shock spectrum, in line with MIL-STD-810E, method no. 516.4, procedure I

EMC		
RF emission		in line with CISPR 11/EN 55011 group 1 class A (for a shielded test setup); the instrument complies with the emission requirements stipulated by EN 55011, EN 61326-1 and EN 61326-2-1 class A, making the instrument suitable for use in industrial environments
Immunity		in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environment [4]

Certifications		VDE-GS, $_{C}$CSA$_{US}$, KC

Calibration interval		1 year

Power supply		
AC supply		100 V to 240 V at 50 Hz to 60 Hz, 100 V to 130 V at 400 Hz, max. 13 A to 4.7 A, in line with MIL-PRF 28800F section 3.5
Power consumption		max. 1000 W
Safety		in line with IEC 61010-1, EN 61010-1, CAN/CSA-C22.2 No. 61010-1-12, UL 61010-1

Mechanical data		
Dimensions (W × H × D)	with R&S®RTP-B20 handles	463 mm × 285 mm × 349 mm (18.23 in × 11.22 in × 13.74 in)
	with shock protection	441 mm × 285 mm × 316 mm (17.36 in × 11.22 in × 12.44 in)
Weight	without options, nominal	18.0 kg (39.68 lb)

[4] Test criterion is displayed noise level within ±1 div for input sensitivity of 5 mV/div.

Options

R&S®RTP-B1

Mixed signal option, additional 16 logic channels

Vertical system

Input channels		16 logic channels (D0 to D15)
Arrangement of input channels		arranged in two logic probes with 8 channels each, assignment of the logic probes to the channels (D0 to D7 or D8 to D15) is displayed on the probe
Input impedance		100 kΩ ± 2 % || ~4 pF (meas.) at probe tips
Maximum input frequency	signal with minimum input voltage swing and hysteresis setting: normal	400 MHz (meas.)
Maximum input voltage		±40 V (V_p)
Minimum input voltage swing		500 mV (V_{pp}) (meas.)
Threshold groups		D0 to D3, D4 to D7, D8 to D11 and D12 to D15
Threshold level	range	±8 V in 25 mV steps
	predefined	CMOS 5.0 V, CMOS 3.3 V, CMOS 2.5 V, TTL, ECL, PECL, LVPECL
Threshold accuracy		±(100 mV + 3 % of threshold setting)
Comparator hysteresis		normal, robust, maximum

Horizontal system

Channel deskew	range for each channel	±200 ns
Channel-to-channel skew		< 500 ps (meas.)

Acquisition system

Sampling rate	max.	5 Gsample/s on each channel
Realtime waveform acquisition rate	max.	> 200 000 waveforms/s
Memory depth	at max. sampling rates	200 Msample for every channel
	at lower sampling rates	100 Msample for every channel
Decimation		pulses lost due to decimation are displayed

Trigger system

Holdoff range	time	100 ns to 10 s, fixed and random
	events	1 event to 2 000 000 000 events

Trigger modes		
Edge	triggers on specified slope (positive, negative or either) in the source signal	
	sources	any channel from D0 to D15 or any logical combination of D0 to D15
Width	triggers on positive or negative pulse of specified width in the source signal; width can be shorter, longer, equal, inside or outside the interval	
	sources	any channel from D0 to D15 or any logical combination of D0 to D15
	pulse width	200 ps to 10 s
Timeout	triggers when the source signal stays high, low or unchanged for a specified period of time	
	sources	any channel from D0 to D15 or any logical combination of D0 to D15
	timeout	200 ps to 10 s
Data2clock	triggers on setup time and hold time violations between a clock signal and a data signal; monitored time interval with a max. width of 200 ns and a position of max. ±1 µs relative to the clock edge	
	data signal	any subset of channels from D0 to D15 or any user-defined bus signal
	clock signal	any channel from D0 to D15

Pattern	triggers when the source goes true or stays true for a period of time shorter, longer, equal, inside or outside a specified range	
	sources	any logical combination of D0 to D15 or any user-defined bus signal
	pulse width	200 ps to 10 s
State	triggers on the slope (positive, negative or either) of the clock signal when data signal matches a user-defined logical state	
	data signal	any logical combination of D0 to D15 or any user-defined bus signal
	clock signal	any channel from D0 to D15
Serial pattern	triggers on a serial data pattern of up to 32 bit; pattern bits may be high (H), low (L) or don't care (X); clock edge slope may be positive, negative or either	
	data signal	any channel from D0 to D15 or any logical combination of D15 to D15
	clock signal	any channel from D0 to D15
	max. data rate	1 Gbps
Serial bus trigger	optional	dedicated software options
	sources	any channel from D0 to D15

Waveform measurements

General features		measurement panels, gate, statistics, long-term analysis and limit check; see features of the base unit
Measurement sources		all channels from D0 to D15 or any logical combination of D0 to D15
Automatic measurements		positive pulse width, negative pulse width, period, frequency, burst width, delay, phase, positive duty cycle, negative duty cycle, positive pulse count, negative pulse count, rising edge count, falling edge count
Additional cursor function		display of decoded bus value at the cursor position

Waveform math

Function		any logical combination of D0 to D15

Search and mark functions

The search function will be available in a future software release.

Display characteristics

Display of logical channels		selectable size and position on screen, diagram configuration by dragging and dropping signal icons
Bus decode	number of bus signals	4
	bus types	unclocked and clocked
	display types	decoded bus, logical signal, bus + logical signal, amplitude signal, amplitude + logical signal, tabulated list (decoded time interval selected with cursors)
	position and size	size and position on screen selectable
	data format of decoded bus	hex, unsigned integer, signed integer, fractional, binary
	data format of amplitude signal	unsigned integer, signed integer, fractional, binary offset
Channel activity display		independent of the scope acquisition, the state (stays low, stays high or toggles) of the channels from D0 to D15 is displayed in the signal icon

R&S®RTP-B6

Arbitrary function/waveform generator, 2 analog channels, 8-bit pattern generator

Analog channels

General		
Output channel		2 channels
Vertical resolution		14 bit
Operating modes		function generator, arbitrary waveform generator, modulation, frequency sweep

Function generator	output of predefined waveforms	
Sample rate		500 Msample/s
Waveforms	sine, square/pulse, ramp, DC, noise, sine cardinal (sinc), Gaussian pulse, Lorentz, exponential fall, exponential rise, cardiac	
Sine	frequency range	1 mHz to 100 MHz
	amplitude flatness (relative to 1 kHz)	
	f ≤ 100 kHz	≤ ±0.1 dB
	100 kHz < f ≤ 60 MHz	≤ ±0.3 dB
	60 MHz < f ≤ 100 MHz	≤ ±0.5 dB
	total harmonic distortion (1 V (V_{pp}) into 50 Ω)	
	f ≤ 100 kHz	≤ –70 dBc (= THD ≤ 0.032 %)
	100 kHz < f ≤ 15 MHz	≤ –55 dBc
	15 MHz < f ≤ 35 MHz	≤ –40 dBc
	35 MHz < f ≤ 100 MHz	≤ –30 dBc
	nonharmonic spurious (1 V (V_{pp}) into 50 Ω)	–65 dBc (meas.)
	phase noise (meas.)	
	f ≤ 25 MHz	≤ –105 dBc (1 Hz) at 1 kHz offset, ≤ –115 dBc (1 Hz) at 10 kHz offset, ≤ –125 dBc (1 Hz) at 100 kHz offset
	25 MHz < f ≤ 100 MHz	≤ –105 dBc (1 Hz) at 1 kHz offset, ≤ –110 dBc (1 Hz) at 10 kHz offset, ≤ –115 dBc (1 Hz) at 100 kHz offset
Square/pulse	frequency range	1 mHz to 30 MHz
	duty cycle (if pulse width limit is not exceeded)	0.01 % to 99.99 %, 0.01 % resolution
	pulse width	≥ 16.5 ns, 0.1 ns resolution
	rise/fall time	
	f ≤ 10 Hz	90 µs (meas.)
	10 Hz < f ≤ 30 MHz	9 ns (meas.)
	overshoot	≤ 2 %
	jitter (cycle-to-cycle)	≤ 40 ps (RMS) (meas.)
Ramp (triangle, sawtooth)	frequency range	1 mHz to 1 MHz
	linearity	≤ 0.1 % (meas.)
	variable symmetry	0 % to 100 %, 0.1 % resolution
DC	level range	
	into 50 Ω	± [3 V – (noise amplitude [V_{pp}] / 2)]
	into open circuit	± [6 V – (noise amplitude [V_{pp}] / 2)]
Noise	amplitude	
	DC	0 V to 6 V (V_{pp}) (into 50 Ω) 0 V to 12 V (V_{pp}) (into open circuit), 4 digits resolution
	all other waveforms	0 % to 100 % of AC signal amplitude, 1 % resolution
	bandwidth	≥ 100 MHz
Sine cardinal (sinc)	frequency range	1 mHz to 2 MHz
Gaussian pulse	frequency range	1 mHz to 10 MHz
Lorentz	frequency range	1 mHz to 5 MHz
Exponential rise/fall	frequency range	1 mHz to 1 MHz
Cardiac	frequency range	1 mHz to 1 MHz

Arbitrary waveform generator	output of user-defined waveforms	
Waveform length		1 sample to 40 Msample on each channel
Sample rate		1 sample/s to 250 Msample/s
Filter bandwidth		100 MHz

Modulation		
Sample rate		500 Msample/s
Modulation types		amplitude modulation (AM), frequency modulation (FM), frequency-shift key modulation (FSK), pulse width modulation (PWM)
Carrier waveform	AM, FM, FSK	sine
	PWM	square/pulse
AM	modulation signals	sine, square, ramp (triangle, sawtooth)
	modulation frequency	1 mHz to 1 MHz
	depth	0 % to 100 %, 0.1 % resolution
FM	modulation signals	sine, square, triangle, ramp, inverse ramp
	modulation frequency	1 mHz to 1 MHz
	frequency deviation	1 mHz to 10 MHz
FSK	modulation signal	50 % duty cycle square wave
	range of frequency 1, frequency 2	1 mHz to 100 MHz
	hop rate	1 mHz to 1 MHz
PWM	modulation signals	sine, square, ramp
	depth	0 % to 99.99 % of the duty cycle, 0.01 % resolution

Frequency sweep	output of a sinusoidal waveform with the frequency changing linearly between the start frequency and the stop frequency within the sweep time	
	sample rate	500 Msample/s
	waveform	sine
	frequency range	1 mHz to 100 MHz
	direction	up (start frequency < stop frequency)
		down (start frequency > stop frequency)
	sweep time	1 ms to 500 s

Two-channel operation	operating modes	independent channels, coupled parameters, differential
	parameter coupling	none, frequency and/or amplitude
	relative phase	–180° to 180°, 0.1° resolution
	channel-to-channel skew	≤ 200 ps (meas.)
	channel-to-channel isolation (each channel with same output amplitude)	
	f ≤ 10 MHz	≥ 60 dB (meas.)
	10 MHz < f ≤ 100 MHz	≥ 40 dB (meas.)

Outputs		
Connectors		BNC female on the rear panel
Function		on, off, inverted
Output impedance		nom. 50 Ω
Overload protection		a short-circuit to ground is tolerated indefinitely, automatic shutoff in case of voltages ≥ +7 V or ≤ –7 V (meas.), automatic shutoff in case of overcurrent, max. –20 V to +20 V without damage (meas.), ESD protection
Amplitude range [5]	sine, square/pulse, ramp, pulse, exponential rise, exponential fall	
	into 50 Ω	10 mV to 6 V (V_{pp}) (frequency ≤ 50 MHz), 10 mV to 4 V (V_{pp}) (frequency > 50 MHz)
	into open circuit	20 mV to 12 V (V_{pp}) (frequency ≤ 50 MHz), 20 mV to 8 V (V_{pp}) (frequency > 50 MHz)
	sine cardinal (sinc)	
	into 50 Ω	10 mV to 3 V (V_{pp})
	into open circuit	20 mV to 6 V (V_{pp})
	Gauss, Lorentz	
	into 50 Ω	10 mV to 2.5 V (V_{pp})
	into open circuit	20 mV to 5 V (V_{pp})
	arbitrary waveforms	
	into 50 Ω	10 mV to 6 V (V_{pp}) (sample rate ≤ 125 Msample/s), 10 mV to 4 V (V_{pp}) (sample rate > 125 Msample/s)
	into open circuit	20 mV to 12 V (V_{pp}) (sample rate ≤ 125 Msample/s), 20 mV to 8 V (V_{pp}) (sample rate > 125 Msample/s)
	resolution	1 mV
	accuracy	± [1% of control + 1 mV (V_{pp})] at 1 kHz
DC offset range	sine, square/pulse, ramp, pulse, exponential rise, exponential fall	
	into 50 Ω	± [3 V – (amplitude [V (V_{pp})] / 2)]
	into open circuit	± [6 V – (amplitude [V (V_{pp})] / 2)]
	sine cardinal (sinc), Gauss, Lorentz	
	into 50 Ω	±0.5 V
	into open circuit	±1 V
	resolution	1 mV
	accuracy	± (2 % of control + 2 mV)
Frequency accuracy		| Δf | ≤ [(timebase accuracy) × (nominal frequency) + 1 µHz] (timebase accuracy: see Horizontal system)

[5] Amplitude is the sum of the AC amplitude and the noise amplitude.

8-bit pattern generator

Function		output of user-defined patterns
Output channels		8 channels, coupled w.r.t. pattern length and data output rate
Pattern length		1 bit to 40 Mbit on each channel
Bit rate		1 bit/s to 40 Mbit/s

Outputs		
Connector		16-pin double row connector, 2.54 mm pitch, located on an adapter board, which is connected via a removable ribbon cable to the R&S®RTO-B6
Output impedance		nom. 330 Ω
Overload protection	reverse input voltage without damage	–0.5 V to +6.5 V (meas.), ESD protection
Amplitude	low level output voltage (I = 100 µA)	
	output voltage	0 V + 0.15 V/– 0.02 V
	accuracy	≤ 0.15 V (meas.)
	high level output voltage	
	setting range	1.2 V to 5.0 V
	resolution	0.1 V
	accuracy	≤ 0.05 V
Rise/fall time		8 ns (meas.)
Overshoot		≤ 5 % (meas.)

R&S®RTP-B7

16 GHz differential pulse source with reference output

Output [6]

Output pulse		two complementary negative going square wave pulse train signals, single-ended or differential operation, fast transition on rising and falling edge, adjustable amplitude and timing parameters, free-running or phase-locked to base unit
Outputs	single-ended operation	single-ended output (OutP)
		single-ended reference output (RefP)
	differential operation	differential output (OutP, OutN)
		differential reference output (RefP, RefN)
Output connectors		2.92 mm female connectors
Reverse DC voltage		0 V
Output impedance	single-ended outputs	nom. 50 Ω
	both differential pairs	nom. 100 Ω
Return loss	≤ 10 GHz	> 15 dB (meas.)
	≤ 20 GHz	> 12 dB (meas.)

DC characteristics [6]

Output high level		0 V ± 10 mV
Output low level setting range		–200 mV to –50 mV adjustable in 10 mV steps
Output low level error	OutP	±2 % of setting ±15 mV
Output low level imbalance	between OutP and RefP, OutN, RefN	±1 dB (meas.)

[6] All four outputs terminated with 50 Ω; all parameters are measured at all four single-ended outputs, unless noted.

Time domain characteristics [6]

Transition time	10 % to 90 %, rising and falling edge, calculated from 0.36/bandwidth	
	output low level: –120 mV to –50 mV	20 ps
	output low level: –200 mV to –130 mV	22 ps
Step response aberrations	for the first 100 ps after step transition	±10 % (meas.)
	for the first 1 ns after step transition	±4 % (meas.)
	until 100 ps before following step transition	±2 % (meas.)
Repetition rate	low frequency mode	5 Hz, 10 Hz, 20 Hz, 50 Hz, 100 Hz, 200 Hz, 500 Hz to 1 MHz
	high frequency mode, phase-locked to base unit	5 MHz, 10 MHz, 25 MHz, 50 MHz, 100 MHz, 250 MHz
	high frequency mode, free-running	5 MHz, 10 MHz, 25 MHz, 50 MHz
Positive duty cycle	measured at 50 % of transition	
	low frequency mode	10 % to 90 %, adjustable in 10 % steps
	high frequency mode	50 %
Duty cycle error	measured at 50 % of transition, at OutP and RefP outputs	
	low frequency mode	±2 % (meas.)
	high frequency mode	±0.1 % (meas.)
Skew	measured at 50 % of transition, between OutP and OutN output	< 0.5 ps (meas.)
Clock accuracy	free-running	±100 ppm (meas.)
	phase-locked to base unit	see Timebase accuracy of base unit

Frequency domain characteristics [6]

Analog bandwidth (–3 dB)	output low level: –120 mV to –50 mV	> 18 GHz (meas.)
	output low level: –200 mV to –130 mV	> 16.5 GHz (meas.)
Spectral magnitude error to ideal step spectrum	≤ 5 GHz	+0.5 dB to –1 dB (meas.)
	≤ 12 GHz	+0.5 dB to –2 dB (meas.)
	≤ analog bandwidth	+0.0 dB to –3 dB (meas.)
Spectral phase error to ideal step spectrum	≤ 5 GHz	–2° to +5° (meas.)
	≤ analog bandwidth	–5° to +15° (meas.)

R&S®RTP-K1

I^2C triggering and decoding		
Protocol configuration	bit rate	up to 3.4 Mbps (auto-detected)
	auto threshold setup	assisted threshold configuration for I^2C triggering and decoding
	device list	associate frame address with symbolic ID
Trigger (included in standard equipment)	source (clock and data)	any input channel or logical channel
	trigger event setup	start, stop, restart, missing ACK, address, data, address + data
	address setup	7 bit or 10 bit address (value in hex, decimal, octal or binary); ACK, NACK or either; read, write or either; R/W bit included in address value or apart; condition =, ≠, ≥, ≤, in range, out of range
	data setup	data pattern up to 8 byte (hex, decimal, octal or binary); condition =, ≠, ≥, ≤, in range, out of range; offset within frame in range from 0 byte to 4095 byte
Decode	source (clock and data)	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical signal, tabulated list, decode layers
	color coding	frame, start/restart, address, R/W bit, data, ACK/NACK, stop, error
	address and data format	hex, decimal, octal, binary, ASCII; symbolic names for user-defined subset of addresses
	decode layer	off, edges, bits
Search	search event setup	combination of start, stop, restart, missing ACK, address, data, address + data
	event settings	same as trigger event settings

SPI triggering and decoding		
Protocol configuration	type	2-wire, 3-wire and 4-wire SPI
	bit rate	auto-detected
	bit order	LSB first, MSB first
	word size	4 bit to 32 bit
	frame condition	SS, timeout
	polarity (MOSI, MISO, SS, CLK)	active high, active low
	phase (CLK)	first edge, second edge
	auto threshold setup	assisted threshold configuration for SPI triggering and decoding
Trigger (included in standard equipment)	source (MOSI, MISO, SS, CLK)	any input channel or logical channel
	bit rate	up to 50 Mbps
	trigger event setup	start of frame, MOSI, MISO, MOSI + MISO
	data setup	data pattern up to 256 bit (hex or binary); condition =, ≠; offset within frame in range from 0 bit to 32767 bit
Decode	source (MOSI, MISO, SS, CLK)	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical signal, tabulated list, decode layers
	color coding	frame, word, error
	data format	hex, decimal, octal, binary, ASCII
	decode layer	edges, bits, words
Search	search event setup	start of frame, MOSI, MISO, MOSI + MISO
	event settings	same as trigger event settings

R&S®RTP-K2

UART/RS-232/RS-422/RS-485 triggering and decoding		
Protocol configuration	bit rate	300 bps to 20 Mbps
	signal polarity	idle low, idle high
	number of bits	5 bit to 9 bit
	bit order	LSB first, MSB first
	parity	odd, even, mark, space, none
	stop bit	1, 1.5 or 2 bit periods
	end of packet	word, timeout, none
	auto threshold setup	assisted threshold configuration for UART triggering and decoding
Trigger (included in standard equipment)	source (TX and RX)	any input channel or logical channel
	trigger event setup	start bit, packet start, data, parity error, break condition
	data setup	data pattern up to 256 bit (hex, decimal, octal, binary or ASCII); condition =, ≠; offset within packet in range 0 bit to 32767 bit
Decode	source (TX and RX)	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	packet, data payload, start error, parity error, stop error
	data format	hex, decimal, octal, binary, ASCII

R&S®RTP-K3

CAN triggering and decoding		
Protocol configuration	signal type	CAN_H, CAN_L
	bit rate	100 bps to 1 Mbps
	sampling point	5 % to 95 % within bit period
	device list	associate frame identifier with symbolic ID, load DBC file content
	auto threshold setup	assisted threshold configuration for CAN triggering and decoding
Trigger	source	any input channel or logical channel
	trigger event setup	start of frame, frame type, identifier, identifier + data, symbolic, error condition (any combination of CRC error, bit stuffing error, form error and ACK error)
	identifier setup	frame type (data, remote or both), identifier type (standard or extended); condition =, ≠, ≥, ≤, in range, out of range
	data setup	data pattern up to 8 byte (hex, decimal, octal or binary); big-endian or little-endian; condition =, ≠, ≥, ≤, in range, out of range
	symbolic setup	message name, signal name; numeric signal condition =, ≠, ≥, ≤, in range, out of range; enumerated signal condition =, ≠, ≥, ≤
Decode	source	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	start of frame, identifier, DLC, data payload, CRC, end of frame, error frame, overload frame, CRC error, bit stuffing error
	data format	hex, decimal, octal, binary, ASCII, symbolic
Search	source	any input channel or logical channel
	search event setup	combination of start of frame, frame type, identifier, identifier + data, error condition (any combination of CRC error, bit stuffing error, form error and ACK error) or only symbolic
	event settings	same as trigger event settings

LIN triggering and decoding		
Protocol configuration	version	1.3, 2.x or SAE J602; mixed traffic is supported
	bit rate	standard bit rate (1.2/2.4/4.8/9.6/10.417/ 19.2 kbps) or user-defined bit rate in range from 1 kbps to 20 kbps
	device list	associate frame identifier with symbolic ID, data length and protocol version
	auto threshold setup	assisted threshold configuration for LIN triggering and decoding
Trigger	source	any input channel
	trigger event setup	start of frame (sync break), identifier, identifier + data, wake-up frame, error condition (any combination of checksum error, parity error and sync field error)
	identifier setup	range from 0d to 63d; select condition =, ≠, ≥, ≤, in range, out of range for trigger “identifier”; select single identifier and condition = for trigger “identifier + data”
	data setup	data pattern up to 8 byte (hex, decimal, octal or binary); condition =, ≠, ≥, ≤, in range, out of range
Decode	source (TX and RX)	any input channel, math waveform, reference waveform
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	frame, frame identifier, data payload, checksum, error condition
	data format	hex, decimal, octal, binary, ASCII
Search	search event setup	combination of start of frame (sync break), identifier, identifier + data, wake-up frame, error condition (any combination of checksum error, parity error and sync field error)
	event settings	same as trigger event settings

R&S®RTP-K8

Ethernet decoding		
Protocol configuration	signal type	one channel, differential
	bit rate	selectable/adjustable
	auto threshold setup	assisted threshold configuration
	source (SDATA)	analog and math channels
	variants	10BASE-T, 100BASE-TX
Decode	display type	decoded bus, logical signal, bus + logical signal, tabulated list, details, decode layers
	color coding	preamble, frame, destination address, source address, data
	data format	hex, octal, binary, signed, unsigned
	decode layer	edges, binary
Search	search event setup	frame, error
	frame	48 bit destination address, 48 bit source address, 16 bit length/type, 32 bit frame check; conditions =, ≠, <, ≤, >, ≥, in range, out of range
	error	preamble, length error

R&S®RTP-K9

CAN-FD triggering and decoding		
Protocol configuration	signal type	CAN_H, CAN_L
	standard	ISO, non-ISO (Bosch)
	bit rate	
	arbitration rate	10 kbps to 1 Mbps
	data rate	10 kbps to 15 Mbps
	sampling point	5 % to 95 % within bit period; independent settings for arbitration phase and data phase
	device list	associate frame identifier with symbolic ID, load DBC file content
	auto threshold setup	assisted threshold configuration
Trigger	source	any input channel or logical channel
	trigger event setup	start of frame, frame type, identifier, identifier + data, symbolic, error condition (any combination of CRC error, bit stuffing error, form error and ACK error)
	identifier setup	frame type (data, remote or both), identifier type (standard or extended); condition =, ≠, ≥, ≤, in range, out of range
	FD bits	FDF, BRS and ESI (0, 1, X)
	data setup	data pattern up to 8 byte in the complete data range (hex, decimal, octal or binary); condition =, ≠, ≥, ≤, in range, out of range
	symbolic setup	message name, signal name; numeric signal condition =, ≠, ≥, ≤, in range, out of range; enumerated signal condition =, ≠, ≥, ≤
Decode	source	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	start of frame, identifier, FD bits, DLC, data payload, CRC, end of frame, error frame, overload frame, CRC error, bit stuffing error
	data format	hex, decimal, octal, binary, ASCII, symbolic
Search	source	any input channel or logical channel
	search event setup	combination of start of frame, frame type, identifier, identifier + data, error condition (any combination of CRC error, bit stuffing error, form error and ACK error) or only symbolic
	event settings	same as trigger event settings

R&S®RTP-K12

Basic jitter analysis		
General description	The R&S®RTP-K12 jitter analysis option extends the functionality of the standard R&S®RTP firmware with a suite of measurement, analysis and visualization tools for signal integrity analysis and jitter characterization.	
Waveform measurements	category	jitter
	measurement functions	cycle-to-cycle jitter, N-cycle jitter, cycle-to-cycle width, cycle-to-cycle duty cycle, time-interval error, data rate, unit interval, skew delay, skew phase; the standard time measurements period, frequency and setup/hold are also available in the jitter category for convenience
	track	measurement results displayed as continuous trace that is time-correlated to the measurement source; applicable to time measurements from categories “jitter” and “amplitude and time”; track trace may be used as source for cursor measurements, automatic measurements, math waveforms and reference waveforms
Waveform math	FFT on track	FFT spectrum of the track trace of measurement results
	CDR transform	recovers clock timing from source waveform with software CDR and generates synthetic clock waveform that is time-correlated to source
Software clock data recovery (CDR)	number of CDR instances	up to 2; independently configurable
	algorithm	phase-locked loop (PLL), constant frequency
	configuration	nominal bit rate, PLL order (first or second), PLL loop bandwidth, PLL damping factor, initial phase alignment, result selection during initial synchronization
Jitter wizard	The jitter wizard assists the user in the step-by-step configuration of the R&S®RTP high-performance oscilloscope for the measurements period/frequency, cycle-by-cycle jitter, time interval error (TIE) and skew.	
Mask testing with eye mask assistant	primary mask shape	
	type	diamond, square, hexagon, octagon
	dimensions	main and secondary height, main and secondary width, depending on selected shape
	position	vertical offset, horizontal offset
	secondary mask shapes	
	locations	any combination of left, right, top, bottom
	position	horizontal and vertical offset with respect to center of primary mask shape

R&S®RTP-K17

High definition mode		
General description	The R&S®RTP-K17 high definition mode increases the numeric resolution of the waveform signal by using digital filtering, leading to a reduced noise. Because of the R&S®RTP digital trigger concept the signals with increased numeric resolution are used as input for triggering.	
Numeric resolution	bandwidth	resolution
	10 kHz to 200 MHz	16 bit
	300 MHz	12 bit
	500 MHz	12 bit
	1 GHz	11 bit
	2 GHz	10 bit
Realtime sampling rate		max. 10 Gsample/s on each channel

R&S®RTP-K19

Zone trigger		
General description	The R&S®RTP-K19 zone trigger enables the triggering on user-defined zones drawn on the display.	
Source		acquired waveforms (input channels), math waveforms
Supported acquisition modes	decimation modes	sample, peak detect, high resolution, root mean square
	high definition mode	with R&S®RTP-K17 option
Zone definition	number of zones	up to 8
	shapes	rectangles, polygones
	types	must intersect, must not intersect
	combination of zones	logical combination of zones of multiple sources using Boolean expressions
Trigger compatibility		compatible with the trigger modes edge, glitch, width, runt, window, timeout, interval, slew rate, data2clock, pattern, state, serial pattern, trigger qualification, and sequence trigger

R&S®RTP-K21

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTP-K21 performs USB 2.0 compliance test measurements with R&S®ScopeSuite, including tests for USB 2.0 (high speed), USB 1.1 (full speed) and USB 1.0 (low speed) with the R&S®RTP. R&S®ScopeSuite supports the R&S®RT-ZF1 USB 2.0 compliance test fixture set and the Allion USB test fixture solutions and the USB-IF signal quality board device/host; R&S®ScopeSuite supports Windows 7, 8 and 10.

Supported USB 2.0 compliance tests		
USB device test	high speed	signal quality (EL_2, 4, 5, 6, 7); packet parameters (EL_21, 22, 25); chirp timing (EL_28, 29, 31); suspend/resume/reset timing (EL_27, 28, 38, 39, 40); test J/K, SE0_NAK (EL_8, 9); receiver sensitivity (EL_16, 17, 18)
	full speed and low speed	full speed signal quality; back voltage; inrush current
USB host test	high speed	signal quality (EL_2, 3, 6, 7); packet parameters (EL_21, 22, 23, 25, 55); chirp timing (EL_33, 34, 35); suspend/resume/reset timing (EL_39, 41); test J/K, SE0_NAK (EL_8, 9)
	full speed and low speed	low speed signal quality downstream; full speed signal quality downstream; drop; droop
USB hub test	high speed	signal quality upstream (EL_2, 4, 6, 7); signal quality downstream (EL_2, 3, 6, 7); jitter downstream (EL_47); packet parameters upstream (EL_21, 22, 25); hub receiver sensitivity upstream (EL_16, 17, 18); repeater downstream (EL_42, 43, 44, 45, 48); repeater upstream (EL_42, 43, 44, 45); chirp timing upstream (EL_28, 29, 31); suspend/resume/reset timing upstream (EL_27, 28, 38, 39, 40); test J/K, SE0_NAK upstream (EL_8, 9); test J/K, SE0_NAK downstream (EL_8, 9)
	full speed and low speed	low speed signal quality downstream; full speed signal quality upstream; full speed signal quality downstream; inrush current upstream; drop downstream; droop downstream; back voltage

R&S®RTP-K22

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTP-K22 performs Ethernet compliance test measurements with R&S®ScopeSuite, including tests for 10BASE-T, 100BASE-TX and 1000BASE-T with the R&S®RTP. R&S®ScopeSuite supports the R&S®RT-ZF2 Ethernet compliance test fixture set; R&S®ScopeSuite supports Windows 7, 8 and 10. The chapters after the test cases refer to IEEE 802.3-2012.

Supported Ethernet 10G compliance tests		
1000BASE-T	with/without disturber	with/without TX_CLK transmitter distortion (40.6.1.2.4)
		peak differential output voltage (40.6.1.2.1)
		maximum output droop (40.6.1.2.2)
		differential output templates (40.6.1.2.3)
	with TX_CLK	jitter master mode (40.6.1.2.5), jitter slave mode (40.6.1.2.5)
	without TX_CLK	jitter master mode (40.6.1.2.5)
	common	MDI return loss (40.8.3.1), common-mode output voltage (40.8.3.3)
100BASE-TX		amplitude domain tests (9.1.2.2, 9.1.3 and 9.1.4)
		rise and fall times (9.1.6)
		peak to peak duty cycle distortion (9.1.8)
		peak to peak transmitter jitter (9.1.9)
		active output interface template (annex J)
		transmitter return loss (9.1.5)
		receiver return loss (9.2.2)
10BASE-T	no TPM	link test pulse template (14.3.1.2.1)
		TP_IDL template (14.3.1.2.1)
		peak differential voltage (14.3.1.2.1)
		harmonic content (14.3.1.2.1)
		output timing jitter (14.3.1.2.3)
	with TPM	link test pulse template (14.3.1.2.1)
		TP_IDL template (14.3.1.2.1)
		MAU template (14.3.1.2.1)
		output timing jitter (14.3.1.2.3)
	common	transmitter return loss (14.3.1.2.2), receiver return loss (14.3.1.3.4)
		common-mode output voltage (14.3.1.2.5)

R&S®RTP-K23

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTP-K23 performs Ethernet compliance test measurements with the R&S®ScopeSuite, including tests for 10GBASE-T with the R&S®RTP. R&S®ScopeSuite supports the R&S®RT-ZF2 Ethernet compliance test fixture set; R&S®ScopeSuite supports Windows 7, 8 and 10. The chapters after the test cases refer to IEEE 802.3-2012.

Supported Ethernet compliance tests		
10GBASE-T		maximum output droop (55.5.3.1)
		transmitter linearity (55.5.3.2)
		transmitter timing jitter master mode (55.5.3.3)
		transmitter timing jitter slave mode (55.5.3.3)
		transmitter power spectral density (55.5.3.4)
		transmitter power level (55.5.3.4)
		transmitter clock frequency (55.5.3.5)
		MDI return loss (55.8.2.1)

R&S®RTP-K24

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTP-K24 performs 100BASE-T1 compliance test measurements with R&S®ScopeSuite. R&S®ScopeSuite supports the R&S®RT-ZF2 Ethernet compliance test fixture set. The chapters after the test cases refer to IEEE P802.3bw.

Supported 100BASE-T1 compliance tests		
100BASE-T1		transmitter output droop (96.5.4.1)
		transmitter distortion with and without disturber (96.5.4.2)
		transmitter timing jitter master mode (96.5.4.3)
		transmitter timing jitter slave mode (96.5.4.3)
		transmitter power spectral density (96.5.4.4)
		transmitter clock frequency (96.5.4.5)
		transmitter peak differential output (96.5.6)
		MDI return loss (96.7.1.3)
		MDI mode conversion Loss (96.8.2.2)
		MDI mode conversion Loss Adapter Verification (96.8.2.2)
		MDI Common Mode Emission (96.5.1.2)

R&S®RTP-K25

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTP-K25 performs 2.5/5G Ethernet compliance test measurements with R&S®ScopeSuite. R&S®ScopeSuite supports the R&S®RT-ZF2 Ethernet compliance test fixture set; R&S®ScopeSuite supports Windows 7, 8 and 10. The chapters after the test cases refer to IEEE P802.3bz.

Supported Ethernet compliance tests		
2.5G/5GBASE-T		maximum output droop (126.5.3.1)
		transmitter nonlinear distortion (126.5.3.2)
		transmitter timing jitter master mode and clock frequency (126.5.3.3 and 126.5.3.5)
		transmitter timing jitter slave mode (126.5.3.3)
		transmitter power spectral density and power level (126.5.3.4)
		MDI return loss (126.6.2.1)

R&S®RTP-K26

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTP-K26 performs D-PHY compliance test measurements with R&S®ScopeSuite. R&S®ScopeSuite supports Windows 7, 8 and 10. The numbers behind the test refer to the MIPI CTS for D-PHY V1.1.

Supported D-PHY compliance tests		
DPHY	group 1 (7 tests): data lane LP-TX signaling requirements	data lane LP-TX Thevenin output high level voltage (V_{OH}) – 1.1.1
		data lane LP-TX Thevenin output low level voltage (V_{OL}) – 1.1.2
		data lane LP-TX from 15 % to 85 % rise time (T_{RLP}) – 1.1.3
		data lane LP-TX from 85 % to 15 % fall time (T_{FLP}) – 1.1.4
		data lane LP-TX slew rate versus C_{LOAD} ($\delta V/\delta t_{SR}$) – 1.1.5
		data lane LP-TX pulse width of exclusive-OR clock ($T_{LP\text{-}PULSE\text{-}TX}$) – 1.1.6
		data lane LP-TX period of exclusive-OR clock ($T_{LP\text{-}PER\text{-}TX}$) – 1.1.7
	group 2 (5 tests): clock lane LP-TX signaling requirements	clock lane LP-TX Thevenin output high level voltage (V_{OH}) – 1.2.1
		clock lane LP-TX Thevenin output low level voltage (V_{OL}) – 1.2.2
		clock lane LP-TX from 15 % to 85 % rise time (T_{RLP}) – 1.2.3
		clock lane LP-TX from 85 % to 15 % fall time (T_{FLP}) – 1.2.4
		clock lane LP-TX slew rate versus C_{LOAD} ($\delta V/\delta t_{SR}$) – 1.2.5
	group 3 (16 tests): data lane HS-TX signaling requirements	data lane HS entry: data lane T_{LPX} value – 1.3.1
		data lane HS entry: data lane $T_{HS\text{-}PREPARE}$ value – 1.3.2
		data lane HS entry: data lane $T_{HS\text{-}PREPARE} + T_{HS\text{-}ZERO}$ value – 1.3.3
		data lane HS-TX differential voltages $V_{OD(0)}$ and $V_{OD(1)}$ – 1.3.4
		data lane HS-TX differential voltage mismatch ΔV_{OD} – 1.3.5
		data lane HS-TX single-ended output voltages $V_{OHHS(DP)}$ and $V_{OHHS(DN)}$ – 1.3.6
		data lane HS-TX static common-mode voltages $V_{CMTX(1)}$ and $V_{CMTX(0)}$ – 1.3.7
		data lane HS-TX static common-mode voltage mismatch $\Delta V_{CMTX(1.0)}$ – 1.3.8
		data lane HS-TX dynamic common-level variations from 50 MHz to 450 MHz $\Delta V_{CMTX(LF)}$ – 1.3.9
		data lane HS-TX dynamic common-level variations above 450 MHz $\Delta V_{CMTX(HF)}$ – 1.3.10
		data lane HS-TX from 20 % to 80 % rise time t_R – 1.3.11
		data lane HS-TX from 80 % to 20 % fall time t_F – 1.3.12
		data lane HS exit: $T_{HS\text{-}TRAIL}$ value – 1.3.13
		data lane HS exit: from 30 % to 85 % post-EoT rise time T_{REOT} – 1.3.14
		data lane HS exit: T_{EOT} value – 1.3.15
		data lane HS exit: $T_{HS\text{-}EXIT}$ value – 1.3.16

DPHY	group 4 (18 tests): clock lane HS-TX signaling requirements	clock lane HS entry: T_{LPX} value – 1.4.1
		clock lane HS entry: $T_{CLK-PREPARE}$ value – 1.4.2
		clock lane HS entry: $T_{CLK-PREPARE} + T_{CLK-ZERO}$ value – 1.4.3
		clock lane HS-TX differential voltages $V_{OD(0)}$ and $V_{OD(1)}$ – 1.4.4
		clock lane HS-TX differential voltage mismatch ΔV_{OD} – 1.4.5
		clock lane HS-TX single-ended output voltages $V_{OHHS(DP)}$ and $V_{OHHS(DN)}$ – 1.4.6
		clock lane HS-TX static common-mode voltages $V_{CMTX(1)}$ and $V_{CMTX(0)}$ – 1.4.7
		clock lane HS-TX static common-mode voltage mismatch $\Delta V_{CMTX(1,0)}$ – 1.4.8
		clock lane HS-TX dynamic common-level variations from 50 MHz to 450 MHz $\Delta V_{CMTX(LF)}$ – 1.4.9
		clock lane HS-TX dynamic common-level variations above 450 MHz $\Delta V_{CMTX(HF)}$ – 1.4.10
		clock lane HS-TX from 20 % to 80 % rise time t_R – 1.4.11
		clock lane HS-TX from 80 % to 20 % fall time t_F – 1.4.12
		clock lane HS exit: $T_{CLK-TRAIL}$ value – 1.4.13
		clock lane HS exit: from 30 % to 85 % post-EoT rise time T_{REOT} – 1.4.14
		clock lane HS exit: T_{EOT} value – 1.4.15
		clock lane HS exit: $T_{HS-EXIT}$ value – 1.4.16
		clock lane HS clock instantaneous: UI_{INST} value – 1.4.17
		clock lane HS clock delta UI: (ΔUI) value – 1.4.18
	group 5 (4 tests): HS-TX clock-to-data lane timing requirements	HS entry: $T_{CLK-PRE}$ value – 1.5.1
		HS exit: $T_{CLK-POST}$ value – 1.5.2
		HS clock rising edge alignment to first payload bit – 1.5.3
		data-to-clock skew ($T_{SKEW[TX]}$) – 1.5.4

R&S®RTP-K37

Spectrogram		
General description	The R&S®RTP-K37 spectrogram option allows advanced signal analysis in the frequency domain.	
Spectrogram	display characteristics	spectrogram display; a separate spectrogram can be created for each FFT display; each FFT segment of a captured acquisition is displayed in a separate spectrogram line
		support of logarithmic frequency x-axis
	number of spectrograms	up to 4
	signal colors	predefined or user-defined color tables for persistence display with the spectrogram
	time lines	in stop mode two separate time lines can be used to navigate through a spectrogram in time; for each time line the relevant FFT segment is displayed in a diagram; the difference in acquisition time between the timelines is displayed
Logarithmic frequency x-axis	display characteristics	logarithmic frequency x-axis for the FFT display with support of analysis tools like cursors and masks
		logarithmic frequency x-axis for the spectrogram display
Waveform measurements	measurement functions	total harmonic distortion variants THD_a, THD_u and THD_f using voltage, overall voltage and overall voltage root means square
	peak list	peak list; diagram labels for easy identification of the peak list entries in the diagram
Waveform math		user-selectable max. hold and min. hold in addition to spectrum averaging, RMS and envelope

R&S®RTP-K40

MIPI RFFE triggering and decoding		
Protocol configuration	signal type	two channel, single-ended
	bit rate	auto-detected, up to 26 Mbps
	auto threshold setup	assisted threshold configuration
	source (SCLK, SDATA)	any two input channels, math waveforms, reference waveforms, or logical channels
Trigger	trigger event setup	sequence start, sequence stop, register 0 write, register write, register read, extended register write, extended register read, extended register write long, extended register read long, error condition types
	sequence start setup	4 bit slave address; conditions =, ≠, <, ≤, >, ≥, in range, out of range
	sequence stop setup	4 bit slave address; conditions =, ≠, <, ≤, >, ≥, in range, out of range
	register 0 write setup	4 bit slave address, 7 bit data word; conditions =, ≠, <, ≤, >, ≥, in range, out of range for each of these options
	register write/read	4 bit slave address, 5 bit register address, 8 bit data word; conditions =, ≠, <, ≤, >, ≥, in range, out of range for each of these options
	extended register write/read	4 bit slave address; 8 bit address, byte count: 0 to 15 (inclusive), data pattern: 1 to 16 bytes (hex or binary); conditions =, ≠, <, ≤, >, ≥, in range, out of range for each of these options; index: 1 to 16 selects the specific data frame byte; conditions =, ≠, <, ≤, >, ≥, in range
	extended register write long/read long	4 bit slave address, 8 bit address, byte count : 0 to 7 (inclusive), data pattern: 0 to 8 bytes (hex or binary); conditions =, ≠, <, ≤, >, ≥, in range, out of range for each of these options; index: 1 to 8 selects the specific data frame byte; conditions =, ≠, <, ≤, >, ≥, in range
	error condition	SSC error; length error, bus park error, parity error, no response, unknown sequence, minimum gap between frames: 2 ns to 100 ns maximum gap between frames: 2 ns to 1 ms
Decode	display type	decoded bus, logical signal, bus + logical signal, tabulated list, decode layers
	color coding	sequence, frame, error
	data format	hex, octal, binary, signed, unsigned
	decode layer	off, edges, bits
	variant	version 2.0
Search	search event setup	sequence start, sequence stop, register 0 write, register write, register read, extended register write, extended register read, extended register write long, extended register read long, error condition types
	event settings	same as trigger event settings

R&S®RTP-K42

MIPI D-PHY triggering and decoding		
Protocol configuration	signal type	clock, data (differential or single-ended)
	bit rate	selectable without clock lane (1 Mbps to 2.5 Gbps), auto detect with clock lane
	source	any input channels, math waveforms, reference waveforms
	variants	D-PHY v. 1.2, CSI-2 v.1.2, DSI v. 1.3
Trigger	trigger event setup	HS start of packet
		HS end of packet
		HS packet header
		HS data
		LP escape mode
		LP lane turnaround
		LP HS request
	HS packet header setup	virtual channel, data type, word count; conditions =, ≠, <, ≤, >, ≥, in range, out of range for data and word count
	HS data	virtual channel, data type, word count, data value, data index; conditions =, ≠, <, ≤, >, ≥, in range, out of range for data count, word count, data value
	LP escape mode	escape mode, data value, data index; conditions =, ≠, <, ≤, >, ≥, in range, out of range for escape mode and data value
Decode	display type	decoded bus, tabulated list, details, decode layers
	color coding	high speed: frames according to trace, cells; low power: escape word, data word
	data format	hex, octal, binary, , signed, unsigned
	decode layer	off, HS edges, HS binary, HS burst bits, HS burst bytes, HS merged bytes, HS merged words, LP edges, LP states, LP active states, LP binary
Search	search event setup	HS start of packet
		HS end of packet
		HS packet header
		HS data
		LP escape mode
		LP lane turnaround
		LP HS request
	event settings	same as trigger event setup

R&S®RTP-K44

MIPI M-PHY triggering and decoding		
Protocol configuration	signal type	up to 4 channels, differential
	bit rate	clock recovery
	source (SDATA)	analog and math channels, reference waveforms
	variants	UniPro 1.6 and M-PHY 4.0
Trigger	trigger event setup	M-PHY burst
		M-PHY adapt
		M-PHY LCC
		UniPro DL_PDU frames
		UniPro PACP frames
		UniPro trigger upper frames
		M-PHY/UniPro errors
Decode	display type	decoded bus, logical signal, bus + logical signal, tabulated list, details, decode layers
	color coding	for different cells/frame types
	data format	K/D symbols; with UniPro additionally: hex, octal, binary, signed, unsigned
	decode layer	off, edges, bits, 8b/10b synbols, LCC bits; with UniPro additionally: filter/descrambler, lane merge, bytes
Search	search event setup	M-PHY burst
		M-PHY adapt
		M-PHY LCC
		UniPro DL_PDU frames
		UniPro PACP frames
		UniPro trigger upper frames
		M-PHY/UniPro errors

R&S®RTP-K50

Manchester and NRZ serial triggering and decoding		
Protocol configuration	signal type	selectable, one channel, differential or single-ended, two channel, differential or single-ended
	bit rate	auto detected, adjustable
	auto threshold setup	assisted threshold configuration
	source	analog, math. channels, logical (only NRZ)
	bit encoding variants	Manchester, Manchester II, NRZ clocked, NRZ unclocked
	properties	active state (high/low), idle state (high/low), clock edge (first/second)
	frame separation	gap, enable signal (only NRZ)
Frame format	frame	multiple frame management, frame identification and sync, variable length frames, variable number of cells
	cells	name, size (bits), numeric format, bit order, color
	file storage of frame format	save/load as xml files
Trigger	variants	all supported bit encodings
	trigger event setup	frame start, pattern, advanced trigger
	frame start	gap, start bit
	pattern	up to 256 bit pattern within 65 535 bit frame
	advanced trigger	frame type (with OR combinations), frame fields (with AND combinations), frame field data; conditions =, ≠, <, ≤, >, ≥, in range, out of range for data count, word count, data value; error types

Decode	display type	decoded bus, logical signal, bus signal, tabulated list, result details, decode layers
	color coding	according to cell configuration table
	data format	according to cell configuration table
	decode layer	edges, binary
Search	event settings	same as advanced trigger settings
Filter	The filter function selects those decode events that shall be shown in the result table. Events that do not match the criteria set will not be displayed in the table when the filter is turned on.	
	settings	same as advanced trigger settings

R&S®RTP-K52

8b10b serial triggering and decoding		
Protocol configuration	signal type	one/two channel, differential, single-ended
	bit rate	selectable/adjustable auto configuration, ideal for bitrate up to 6.25 Gbit/s
	auto threshold setup	assisted threshold configuration
	one click setup	convenient way for perfect decode results; auto scaling of waveforms, auto threshold and bitrate estimation on one click
	source (differential, single-ended D+/D–)	full combination of either analog, math, reference channels
	variants	all layer 1 (physical layer) encoded 8b/10b protocols, recommended for Ethernet, FibreChannel 1G, 2G, PCI Express®, Serial ATA, Serial Rapid IO (SRIO), XAUI
Trigger	trigger event setup	symbols, errors
	symbols	K/D symbol (8 bit/10 bit), complex expression (combination of K/D symbols, wildcards, disparity)
	errors	disparity, glitching and unknown symbol
Decode	display type	decoded bus, bus signal, tabulated list, details, decode layers
	color coding	sync symbol, K symbols, data (Dx.y) coding and error coding
	data format	hex, 10 bit and K/D representation
	decode layer	edges, bits
Search	search event setup	symbols, errors
	event settings	same as trigger event settings

R&S®RTP-K55

MDIO serial triggering and decoding		
Protocol configuration	bit rate	up to 5 Mbps (auto-detected)
	auto threshold setup	assisted threshold configuration for MDIO triggering and decoding
	device list	associate frame address with symbolic ID
Trigger	source (clock and data)	any input channel or logical channel
	trigger event setup	start, stop, ST, OP, PHY address, register address, data
	ST setup	01 (clause 22), 00 clause 45, any
	OP setup	address, write, post read, read, any
	PHY address setup	5 bit address (hex, decimal, octal or binary); equal
	PHY register (clause 22)/device type (clause 45) setup	5 bit value (hex, decimal, octal or binary); equal
	data (clause 22)/data/address (clause 45)	16 bit value (hex, decimal, octal or binary); equal
Decode	source (clock and data)	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical signal, tabulated list, decode layers
	color coding	frame, PHY address, PHY register, address, data, turnaround
	PHYAD/PRTAD	symbolic names for user defined addresses
	address/data field format	hex, decimal, octal, binary, ASCII, signed, unsigned
	decode layer	final, edges, binary
Search	source (clock and data)	any input channel, math waveform, reference waveform, logical channel
	search event setup	start, stop, ST, OP, PHY address, register address, data
	event settings	same as trigger event settings

R&S®RTP-K57

IEEE 100BASE-T1 serial triggering and decoding		
Protocol configuration	signal type	one channel differential, two channels single-ended, optional additional use of reverse channels for signal improvement: one channel differential, two channels single-ended
	symbol rate	66.667 Msymbol/s, adjustable for testing
	thresholds	upper/lower, assisted threshold configuration
	source	any analog input channels, math waveforms, reference waveforms
	polarity	normal, inverted
	mode	slave, master
Trigger	trigger event setup	frame start MAC frame idle frame error conditions
	MAC frame setup	destination address (condition =, ≠, <, >, ≥, ≤, in range, out of range), source address (condition =, ≠, <, >, ≥, ≤, in range, out of range), length/type (condition =, ≠, <, >, ≥, ≤, in range, out of range), frame check (condition =, ≠, <, >, ≥, ≤, in range, out of range), data (condition =, ≠, <, >, ≥, ≤, in range, out of range), data index (condition =, <, >, ≥, ≤, range)
	error condition setup	preamble error, CRC error, SFD error
Decode	display type	decoded bus, tabulated list, details, decode layers
	color coding	for different cells types
	data format	hex, octal, binary, signed, unsigned
	decode layer	reversed bits, descrambled bits, scrambled bits, ternary symbols
Search	search event setup	frame start MAC frame idle frame error conditions
	event settings	same as trigger event settings

R&S®RTP-K60

USB 1.0/1.1/2.0/HSIC triggering and decoding		
Protocol configuration	signal type	single-ended, differential
	protocol type	low, full, high speed and HSIC
	bit rate	standard bit rates (1.5/12/480 Mbit/s)
	source	any input channel
	probe type	
	for low and full speed	single-ended probe
	for high speed	differential probe (R&S®RT-ZDx)
	for HSIC	single-ended probe(R&S®RT-ZSx)
	auto threshold setup	assisted threshold configuration for USB triggering and decoding
Trigger	trigger event setup	start of packet, end of packet, PID token (IN, OUT, SETUP, SOF), PID data (Data0, Data1, Data2 [7], MData [7]), PID handshake (ACK, NAK, STALL, NYET [7]), PID special (PRE [8], ERR [7], SPLIT [7], PING [7]); bus state (reset [8], resume [8], suspend [8]); error condition
	address, endpoint and frame setup SC, port, SEU, ET check (SPLIT) [8]	condition =, ≠, ≥, ≤, in range, out of range
	data setup	data pattern up to 4 byte (hex, decimal, octal, binary or ASCII), bit separately configurable (1, 0 or don't care); condition =, ≠; position based or window based triggering (first occurrence in packet payload)
	error condition	any error, PID error, CRC5 error, CRC16 error, bit stuffing error, unexpected PID, SE1 error [8] and glitching error
Decode	source	any input channel, math waveform
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	packet identifier, payload length, frame, address, endpoint , data payload, CRC5, CRC16, error condition
	data format	hexadecimal, decimal, octal, binary, ASCII, unsigned
Search	search event setup	combination of start of packet, PID token (IN, OUT, SETUP, SOF), PID data (Data0, Data1, Data2 [7], MData [7]), PID handshake (ACK, NAK, STALL, NYET [7]), PID special (PRE [8], ERR [7], SPLIT [7], PING [7]); error condition (any error, PID error, CRC5 error, CRC16 error, bit stuffing error, unexpected PID, SE1 error [8] and glitching error)
	address, endpoint and frame setup SC, port, SEU, ET check (SPLIT)	condition =, ≠, ≥, ≤, in range, out of range
	data setup	data pattern up to 4 byte (hex, decimal, octal, binary or ASCII), bit separately configurable (1, 0 or don't care); condition =, ≠; position based or window based triggering (first occurrence in packet payload)
	error condition	any error, PID error, CRC5 error, CRC16 error, bit stuffing error, unexpected PID, SE1 error [8] and glitching error

[7] Only available in high speed and HSIC.

[8] Only available in low and full speed.

R&S®RTP-K61

USB 3.1 Gen 1 serial triggering and decoding		
Protocol configuration	signal type	one channel
	bit rate	auto detected
	auto threshold setup	supported
	source	any analog input channels, math channels, reference channels
	scrambling	selectable
Trigger	trigger event setup	frame start
		frame content
		errors
	frame content	USB packet types: TSEQ, TSET1, TSET2, set link function, U2 inactivity timeout, vendor device test, port capability, port configuration, port, config. resp., link delay meas, ACK, NRDY, ERDY, STATUS, STALL, function wake, latency tolerance, bus interval, adjust, host role request, sublink speed, ping, ping response, data packet header, data packet payload, DPP aborted, isochronous timestamp, link command, info, BRST, BDAT, BERC, BCNT, idle; fields according to selected USB packet with content conditions =, ≠, <, >, ≥, ≤, in range, out of range
	errors	CRC, length, value out of range
Decode	display type	decoded bus, tabulated list, details, decode layers
	color coding	cell and frame types
	data format	hexadecimal, octal, binary, ASCII, signed, unsigned, 8b/10b symbols
	decode layer	edges, bits, scrambled symbols, descrambled symbols, bytes
Search	search event setup	frame start
		frame content
		errors
	event settings	same as trigger event settings

R&S®RTP-K63

USB power delivery serial triggering and decoding		
Protocol configuration	signal type	one channel
	bit rate	auto detected
	source	any analog input channel, logical channels, math channels, reference channels
	thresholds	data, advertisements
	data details	detailed breakdown selectable
Trigger	trigger event setup	frame start
		frame content
		errors
	frame content	extended, NumDataObjs, MsgID, PwrRole/Plug, Rev, DataRole, MsgType, voltage advertisements (content conditions =, ≠, <, >, ≥, ≤, in range, out of range)
	errors	4b/5b, preamble, CRC, length, SOP warning
Decode	display type	decoded bus, logical signal, bus + logical signal, tabulated list, details, decode layers
	color coding	cell and frame types
	data format	hex, octal, binary, signed, unsigned
	decode layer	edges, bits, 4b5b symbols
Search	search event setup	frame start
		frame content
		errors
	event settings	same as trigger event settings

R&S®RTP-K64

USB 3.1 SSIC serial decoding and triggering		
Protocol configuration	signal type	up to 4 lanes differential
	bit rate	auto detected
	source	any analog input channels, math channels, reference channels
	scrambling	selectable
Trigger	trigger event setup	frame start
		frame content
		errors
	frame content	USB packet types: TSEQ, TSET1, TSET2, set link function, U2 inactivity timeout, vendor device test, port capability, port configuration, port, config. resp., link delay meas, ACK, NRDY, ERDY, STATUS, STALL, function wake, latency tolerance, bus interval, adjust, host role request, sublink speed, ping, ping response, data packet header, data packet payload, DPP aborted, isochronous timestamp, link command, info, BRST, BDAT, BERC, BCNT, idle; fields according to selected USB packet with content conditions =, ≠, <, >, ≥, ≤, in range, out of range
	errors	CRC, length, value out of range
Decode	display type	decoded bus, tabulated list, details, decode layers
	color coding	cell and frame types
	data format	hex, octal, binary, signed, unsigned
	decode layer	off, edges, bits, bytes, 8b/10b symbols, LCC bits, descrambler, lane merge
Search	search event setup	frame start
		frame content
		errors
	event settings	same as trigger event settings

R&S®RTP-K72

The R&S®RTP-K72 option is suitable for the R&S®RTP064 and the R&S®RTP084.

PCI Express 1.1/2.0 serial triggering and decoding		
Protocol configuration	signal type	up to four channels (×1, ×2, ×4 link size) differential signals
	bit rate	predefined 2.5 Gbit/s for Gen 1 and 5 Gbit/s for Gen 2
	source	any analog input channels, math channels, reference channels
Trigger	trigger event setup	TLP (transaction layer packets), DLLP (data layer packets), ordered sets, errors
	TLP (transaction layer packets)	any type, memory request (32 bit /64 bit, R/W, ordering, snoop, seq. number, Requester ID), I/O transactions, configuration requests, message requests (incl. routing and message code), completion packets (status, completer ID), atomic operation (FetchAdd, SWAP, CAS) for 32 bit/64 bit
	DLLP (data layer packets)	any type, Ack and Nak (seq. number), InitFC1, InitFC2, updateFC (credit type C, NP, Cpl and virtual channel), power management with PM type, vendor packet format. multi-root I/O virtualization (MRDLLP): MRInit (phase, VH FC, mixed type, authorized, device/port type), MRReset (A, VH Group), MRUpdateFC, MRInitFC1 and MRInitFC2 (VL number, VH absent, TLP type, credit type)
	ordered sets	SKP OS, training sequence (TS1, TS2), fast training sequence (FTS), electrical idle OS, electrical idle exit OS, compliance & modified compliance pattern
	errors condition setup	CRC16, ECRC, LCRC, disparity, invalid packets (corrupt header or length errors)
Decode	display type	decoded bus, tabulated list, decode layers, detailed result display for packets
	color coding	TLP, DLLP, K-code, D-code, ordered sets, errors
	data format	K/D symbol, 8 bit format (hex)
	decode layer	8b10b, descrambled 8b10b, bits
Search	search event setup	TLP, DLLP, ordered sets, errors
	event settings	same as trigger event settings

R&S®RTP-K81

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTP-K81 performs PCIe 1.x/2.0 (up to 2.5GT/s) compliance test measurements with R&S®ScopeSuite. R&S®ScopeSuite supports Windows 7, 8 and 10. The option can only be used with an R&S®RTP064 and an R&S®RTP084. The chapters after the category refer to PCI Express Base Specification Revision 1.1 and 2.1.

Supported PCIe compliance tests		
PCIe 1.x	signal quality (4.3.3)	mean unit interval
		data rate
		template tests
		min eye width
		median to max jitter
		differential output voltage
PCIe 1.x	reference clock (1.32)	differential input high voltage
		differential input low voltage
		duty cycle
		average clock period
		rising edge rate
		falling edge rate
PCIe 2.0	signal quality (4.3.3)	mean unit interval
		data rate
		template tests
		min eye width
		median to max jitter
		differential output voltage

R&S®RTP-K86

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTP-K86 performs Energy Efficient Ethernet (EEE) compliance test measurements with R&S®ScopeSuite, including tests for 10BASE-Te, 100BASE-TX EEE and 1000BASE-T EEE with the R&S®RTP. R&S®ScopeSuite supports the R&S®RT-ZF4 and R&S®RT-ZF5 Ethernet compliance test fixture set. R&S®ScopeSuite supports Windows 7, 8 and 10. The chapters after the test cases refer to IEEE 802.3-2012.

Supported EEE compliance tests		
1000BASE-T EEE (requires R&S®RT-ZF5)		quiet time (78.2)
		refresh time (master) (78.2)
		refresh time (slave) (78.2)
		wake state levels (40.6.1.2.7)
		transmitter timing jitter with TX_TCLK (master) (40.6.1.2.5)
		transmitter timing jitter with TX_TCLK (slave) (40.6.1.2.5)
		transmitter timing jitter without TX_TCLK (master) (40.6.1.2.5)
		transmitter timing jitter without TX_TCLK (master) (40.6.1.2.5)
100BASE-TX EEE (requires R&S®RT-ZF5)		sleep time (24.2.3.4 and 78.2)
		LPI quiet time (24.2.3.4 and 78.2)
		LPI refresh time (24.2.3.4 and 78.2)
		LPI transmitter timing jitter (24.2.3.4 and 78.2)
		transmit wake time (24.2.3.4 and 78.2)
10BASE-Te (requires R&S®RT-ZF4)	no TPM	link test pulse template (14.3.1.2.1)
		TP_IDL template (14.3.1.2.1)
		peak differential voltage (14.3.1.2.1)
		harmonic content (14.3.1.2.1)
		output timing jitter (14.3.1.2.3)
	with TPM	link test pulse template (14.3.1.2.1)
		TP_IDL template (14.3.1.2.1)
		MAU template (14.3.1.2.1)
		output timing jitter (14.3.1.2.3)
	common	transmitter return loss (14.3.1.2.2), receiver return loss (14.3.1.3.4)
		common-mode output voltage (14.3.1.2.5)

R&S®RTP-K87

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTP-K87 performs 1000BASE-T1 compliance test measurements with R&S®ScopeSuite. R&S®ScopeSuite supports the R&S®RT-ZF6 frequency converter; R&S®ScopeSuite supports Windows 7, 8 and 10. The chapters in front of the test cases refer to IEEE 802.3bp-2016.

Supported 1000BASE-T1 compliance tests		
1000BASE-T1		97.5.3.3 transmitter timing jitter master mode
		97.5.3.3 transmitter timing jitter slave mode
		97.5.3.3 transmitter timing MDI jitter
		97.5.3.6 transmitter clock frequency
		97.5.3.2 transmitter distortion
		97.5.3.4 transmitter power spectral density (PSD)
		97.5.3.4 transmitter power level
		97.5.3.5 transmitter peak differential output
		97.5.3.1 maximum output droop
		97.7.2.1 MDI return loss
		97.7.2.2 MDI mode conversion loss

R&S®RTP-K91

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTP-K91 performs DDR3 (JESD79-3F), DDR3L(JESD79-3-1A.01) and LPDDR3 (JEDS209-3C) compliance test measurements with R&S®ScopeSuite. Furthermore it enables the DDR3 decode capability to separate read and write bursts as well as the eye analysis function for mask testing on the oscilloscope. R&S®ScopeSuite supports Windows 7, 8 and 10.

Supported DDR3 compliance tests		
Timing tests	clock timing (12.1)	tCK(avg) (12.1.1)
		tCK(abs) (12.1.2)
		tCL(avg) (12.1.3)
		tCH(avg) (12.1.3)
		tJIT(per) (12.1.4)
		tJIT(duty) (12.1.4)
		tJIT(cc) (12.1.5)
		tERR(nper) (12.1.6)
	data timing (4.13.2, 13.4, 13.6)	tDS(base) (13.6)
		tDH(base) (13.6)
		tDS(derate) (13.6)
		tDH(derate) (13.6)
		tHZ (4.13.2)
		tLZ (4.13.2)
		tDIPW (13.4 note 28)
		tDQSQ (4.13.2)
		tQH (4.13.2)
	strobe timing (4.13, 4.14, 8.3.1)	tDQSCK (4.13.2)
		tLZ (4.13.2)
		tHZ (4.13.2)
		tRPRE (4.13.2)
		tRPST (4.13.2)
		tQSH (4.13.2)
		tQSL (4.13.2)
		tDQSS (4.14.2)
		tDQSH (4.14.2)
		tDQSL (4.14.2)
		tDSS (4.14.2)
		tDSH (4.14.2)
		tWPST (4.14.2)
		tWPRE (4.14.2)
		tDVAC (strobe) (8.3.1)
		tDVAC (clock) (8.3.1)

	command timing (13.5)	tIS (13.5)
		tIS (derated) (13.5)
		tIH (13.5)
		tIH (derated) (13.5)
		tIPW (13.5)
		tVAC (CA) (13.5)
	address timing (13.5) DDR3 and DDR3L	tIS (13.5)
		tIS (derated) (13.5)
		tIH (13.5)
		tIH (derated) (13.5)
		tIPW (13.5)
		tVAC (CA) (13.5)
	address timing (4.2) LPDDR3	tISCA (4.2)
		tIHCA (4.2)
		tIPWCA (4.2)
		tVAC (CA) (13.5)
	chip select timing (13.5) DDR3 and DDR3L	tIS (13.5)
		tIS (derated) (13.5)
		tIH (13.5)
		tIH (derated) (13.5)
		tIPW (13.5)
	chip select timing (4.2) LPDDR3	tISCS (4.2)
		tIHCS (4.2)
		tIPWCS (4.2)
		tVAC(CS) (11.5)
Electrical tests single-ended measurements	input slew rate for ADD and CMD DDR3 and DDR3L (8.5, 13.5) LPDDR3 (7.6, 11.5)	SR(tIS) rising
		SR(tIS) falling
		SR(tIH) rising
		SR(tIH) falling
	input slew rate for DQ and DM DDR3 and DDR3L (8.5, 13.6) LPDDR3 (7.6, 11.6)	SR(tIS) rising
		SR(tIS) falling
		SR(tIH) rising
		SR(tIH) falling
	AC and DC input levels for ADD and CMD DDR3(8.1.1) DDR3L(3.1) LPDDR3(7.1.1)	VIH (AC)
		VIL (AC)
		VIH (DC)
		VIL (DC)
	AC and DC input levels for DQ and DM (8.1.2)	VIH (AC)
		VIL (AC)
		VIH (DC)
		VIL (DC)
	AC input levels for CK and DQS (8.3.3)	VSEH (AC)
		VSEL (AC)
	output slew rate for DQ (9.3)	SRQse rising
		SRQse falling
	AC and DC output levels for DQ (9.2)	VOH(AC)
		VOL(AC)
		VOH(DC)
		VOL(DC)
	AC overshoot and undershoot for ADD and CMD (9.6.1)	overshoot amplitude
		overshoot area
		undershoot amplitude
		undershoot area
	AC overshoot and undershoot for CK, DQ, DQS and DM (9.6.2)	overshoot amplitude
		overshoot area
		undershoot amplitude
		undershoot area

Electrical tests differential measurements	AC input levels for CK and DQS (8.3)	VIHdiff (AC)
		VILdiff (AC)
	AC differential cross point voltage for CK and DQS (8.4)	VIX (AC)
	differential output slew rate for DQS (9.4)	SRQdiff Rising
		SRQdiff Falling
	differential AC output levels for DQS (9.2)	VOHdiff(AC)
		VOLdiff(AC)
Debug	trigger write cycle	configures the scope to trigger on a write cycle
	trigger read cycle	configures the scope to trigger on a read cycle
DDR3 decoding		
Protocol configuration	signal type	DQ, DQS
	bit rate	adjustable
	threshold setup	manual threshold / hysteresis configuration
	source	analog channels
Decode	display type	decoded bus, tabulated list, details
	color coding	read frame, write frame
	data format	hex, octal, binary, signed, unsigned
	decode layer	edges, bits, words
Search	search event setup	frame content, error
	frame content	data; conditions =, ≠, <, ≤, >, ≥, in range, out of range
	error	length, frame incomplete
DDR3 eye diagram		
General description	The DDR3 eye diagram allows the user to generate eye diagrams from long multi-period acquisitions of clock signals and serial data signals. It allows the fine control of the signal content that contributes to the eye diagram and enables the development advanced analysis, measurement, mask test and navigation functions.	
General configuration	number of eye diagram instances	up to 4; independently configurable
	main source	analog channels, math channels, reference channels
	timing reference source	analog channels, math channels, reference channels
	horizontal settings	range, position; expressed in absolute time or relative to user-defined bit rate
Display	persistence	50 ms to 50 s, or infinite
	trace colors	predefined or user-defined color tables
	eye stripe	displays position of eye diagram slices and masks violations time-correlated to the main source waveform; always enabled, for mask tests only, disabled.
Qualification	gate	
	position	start, stop; absolute time or relative to display in percent
	coupling	none, cursor #, zoom #
	signal	
	source	analog channels, math channels, reference channels
	condition	greater than, less than; relative to selected reference level
Filter	DDR3 protocol	
	frame type	any, read frame, write frame
	error	length
	bit sequence	
	mode	all, level transition, constant level, bit pattern
	bit pattern setup	up to 8 prefix bits and up to 5 suffix bits with respect to central eye diagram bit

Mask testing	mask test results	
	counters	acquisitions, slices, sample hits, slice hits, fail rate
	violation details	number and position of mask violation, expressed as time instant and slice index
	navigation and zoom	use zoom coupling to navigate to violation upon clicking the corresponding table item

R&S®RTP-K99

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. It requires matching compliance test options (see below). R&S®RTP-K99 makes it possible to automate the supported compliance options remotely. After remote execution of a test case the user can collect the results to process them in a proprietary software to create own reports.

Remote API to execute test cases of R&S®ScopeSuite		
API language		C#
Supported options	R&S®RTP-K22	100BASE-TX
	R&S®RTP-K24	100BASE-T1

R&S®RTP-K121

Deembedding base option		
General description	The R&S®RTP-K121 deembedding base option allows waveform correction based on S-parameters of the involved measurement blocks.	
Source		channel 1, channel 2, channel 3, channel 4,
Signal types		single-ended signals
		full differential signals based on differential probes
S-parameter files		s2p-files and s4p-files
Types of blocks		cables, connectors, fixtures and customer defined blocks
Maximum number of blocks		10

R&S®RTP-K122

Realtime deembedding extension		
General description	The R&S®RTP-K122 realtime deembedding extension option allows waveform correction based on S-parameters in realtime. This option is an extension to the R&S®RTP-K121 deembedding base option. For details, see R&S®RTP-K121 option.	
Realtime waveform acquisition rate		see acquisition system

Ordering information

Designation	Type	Order No.
Base unit (including standard accessories: R&S®RT-ZA16 precision BNC to SMA adapter (2 pieces), quick start guide, power cord)		
High-performance oscilloscope		
4 GHz, 50 Msample memory	R&S®RTP044	1320.5007.04
6 GHz, 50 Msample memory	R&S®RTP064	1320.5007.06
8 GHz, 50 Msample memory	R&S®RTP084	1320.5007.08
Hardware options (plug-in)		
Mixed signal option, 400 MHz	R&S®RTP-B1	1333.2424.02
Digital extension port for R&S®RT-ZVC usage with R&S®RTP oscilloscope, included in R&S®RTP-B1	R&S®RTP-B1E	1337.9581.02
Arbitrary waveform generator, 100 MHz, 2 analog channels, 8-bit pattern generator	R&S®RTP-B6	1333.2418.02
16 GHz differential pulse source	R&S®RTP-B7	1333.2001.02
Adapter rear option slot	R&S®RTP-B21	1338.0507.02
Additional solid state disk	R&S®RTP-B19	1337.9498.02
Memory upgrade, 100 Msample per channel	R&S®RTP-B101	1337.9500.02
Memory upgrade, 200 Msample per channel	R&S®RTP-B102	1337.9517.02
Memory upgrade, 500 Msample per channel	R&S®RTP-B105	1337.9523.02
Memory upgrade, 1 Gsample per channel	R&S®RTP-B110	1337.9530.02
Bandwidth upgrades [9]		
Upgrade of the R&S®RTP044 to 6 GHz bandwidth	R&S®RTP-B0406	1337.9398.02
Upgrade of the R&S®RTP044 to 8 GHz bandwidth	R&S®RTP-B0408	1337.9400.02
Upgrade of the R&S®RTP064 to 8 GHz bandwidth	R&S®RTP-B0608	1337.9430.02
Software options		
Serial triggering and decoding		
I^2C/SPI serial triggering and decoding	R&S®RTP-K1	1337.8604.02
UART/RS-232/RS-422/RS-485 serial triggering and decoding	R&S®RTP-K2	1337.8610.02
CAN/LIN serial triggering and decoding	R&S®RTP-K3	1337.8627.02
Ethernet serial decoding	R&S®RTP-K8	1337.8633.02
CAN-FD serial triggering and decoding	R&S®RTP-K9	1337.8640.02
MIPI RFFE serial triggering and decoding	R&S®RTP-K40	1337.8733.02
MIPI D-PHY serial triggering and decoding	R&S®RTP-K42	1337.8740.02
MIPI M-PHY serial triggering and decoding	R&S®RTP-K44	1337.8756.02
Manchester and NRZ serial triggering and decoding	R&S®RTP-K50	1329.7531.02
8b10b serial decoding	R&S®RTP-K52	1329.7548.02
MDIO serial triggering and decoding	R&S®RTP-K55	1329.7554.02
IEEE 100BASE-T1 serial triggering and decoding	R&S®RTP-K57	1800.6548.02
USB 1.0/1.1/2.0/HSIC serial triggering and decoding	R&S®RTP-K60	1337.8791.02
USB 3.1 Gen 1 serial triggering and decoding	R&S®RTP-K61	1337.8804.02
USB power delivery serial triggering and decoding	R&S®RTP-K63	1337.8810.02
USB 3.1 SSIC serial triggering and decoding	R&S®RTP-K64	1337.9117.02
PCI Express 1.1/2.0 serial triggering and decoding	R&S®RTP-K72	1337.8827.02
Compliance tests		
USB 2.0 compliance test	R&S®RTP-K21	1337.8685.02
Ethernet compliance test (10/100/1000BASE-T)	R&S®RTP-K22	1337.8691.02
Ethernet compliance test (10GBASE-T)	R&S®RTP-K23	1337.8704.02
IEEE 100BASE-T1 (BroadR-Reach®) compliance test	R&S®RTP-K24	1800.6531.02
Ethernet compliance test (2.5G/5G-BASE-T)	R&S®RTP-K25	1337.8710.02
MIPI-D-PHY compliance test	R&S®RTP-K26	1337.8727.02
PCI Express 1.1/2.0 compliance test	R&S®RTP-K81	1337.8885.02
Energy-efficient Ethernet compliance test (10M/100M/1G-BASE-T)	R&S®RTP-K86	1337.8833.02
IEEE 1000BASE-T1 compliance test	R&S®RTP-K87	1800.6554.02
DDR3/DDR3L/LPDDR3 signal integrity debug and compliance test	R&S®RTP-K91	1337.8840.02
R&S®ScopeSuite automation	R&S®RTP-K99	1326.4425.02
Analysis		
Jitter analysis	R&S®RTP-K12	1337.8656.02
High definition mode	R&S®RTP-K17	1337.8856.02
Zone trigger	R&S®RTP-K19	1317.8879.02
Spectrogram	R&S®RTP-K37	1338.1110.02
Deembedding base option	R&S®RTP-K121	1326.3064.02
Realtime deembedding extension	R&S®RTP-K122	1326.3070.02

[9] The bandwidth upgrade is performed at a Rohde & Schwarz service center, where the oscilloscope will also be calibrated.

Designation	Type	Order No.
Probes		
8.0 GHz transmission line probe, 10:1, 500 Ω, 0.3 pF, 20 V (RMS)	R&S®RT-ZZ80	1409.7608.02
3.0 GHz active voltage probe, single-ended, 1 MΩ, 0.8 pF	R&S®RT-ZS30	1410.4309.02
6.0 GHz active voltage probe, single-ended, 1 MΩ, 0.3 pF	R&S®RT-ZS60	1418.7307.02
4.0 GHz power rail probe, 1:1, low noise, 50 kΩ, large offset range ±60 V	R&S®RT-ZPR40	1800.5406.02
1.0 GHz active voltage probe, differential, 1 MΩ, 0.6 pF, incl. R&S®RT-ZA15	R&S®RT-ZD10	1410.4715.02
1.5 GHz active voltage probe, differential, 1 MΩ, 0.6 pF	R&S®RT-ZD20	1410.4409.02
3.0 GHz active voltage probe, differential, 1 MΩ, 0.6 pF	R&S®RT-ZD30	1410.4609.02
4.5 GHz active voltage probe, differential, 1 MΩ, 0.4 pF	R&S®RT-ZD40	1410.5205.02
6.0 GHz modular probe amplifier, differential, 400 kΩ, multimode	R&S®RT-ZM60	1419.3105.02
9.0 GHz modular probe amplifier, differential, 400 kΩ, multimode	R&S®RT-ZM90	1419.3205.02
Tip cable, solder in, length: 15 cm, multimode compatible	R&S®RT-ZMA10	1419.4301.02
Tip cable, square pin, for 1.27 mm pin header, length: 15 cm, multimode compatible	R&S®RT-ZMA12	1419.4324.02
Tip cable, quick connect, for solder in resistor connection, length: 15 cm, multimode	R&S®RT-ZMA15	1419.4224.02
Browser module, variable span from 0.5 mm to 8 mm, spring-loaded, multimode	R&S®RT-ZMA30	1419.4353.02
SMA module, 2.92 mm/3.5 mm/SMA, differential, 100 Ω, DC termination, multimode	R&S®RT-ZMA40	1419.4201.02
Extended temperature kit, 1 m matched cable pair, multimode compatible	R&S®RT-ZMA50	1419.4218.02
Multi-channel power probe, 2 × 4 voltage/current channels	R&S®RT-ZVC04	1326.0259.04
Multi-channel power probe, 2 × 2 voltage/current channels	R&S®RT-ZVC02	1326.0259.02
Probe set for E and H near-field measurements, 9 kHz to 1 GHz	R&S®HZ-14	1026.7744.03
Compact probe set for E and H near-field measurements, 30 MHz to 3 GHz	R&S®HZ-15	1147.2736.02
3 GHz, 20 dB preamplifier, 100 V to 230 V power adapter, for R&S®HZ-15	R&S®HZ-16	1147.2720.02
Probe accessories		
Spare accessory set for R&S®RT-ZS10/10E/20/30	R&S®RT-ZA2	1416.0405.02
Pin set for R&S®RT-ZS10/10E/20/30	R&S®RT-ZA3	1416.0411.02
Mini clips	R&S®RT-ZA4	1416.0428.02
Micro clips	R&S®RT-ZA5	1416.0434.02
Lead set	R&S®RT-ZA6	1416.0440.02
Pin set for R&S®RT-ZD20/30	R&S®RT-ZA7	1417.0609.02
Pin set for R&S®RT-ZD40	R&S®RT-ZA8	1417.0867.02
External attenuator, 10:1, 2.0 GHz, 70 V DC, 46 V AC (peak)	R&S®RT-ZA15	1410.4744.02
Power rail browser kit	R&S®RT-ZA25	1800.5329.00
Pigtail cable, solder-in, length: 15 cm, for R&S®RT-ZPR20	R&S®RT-ZA26	1800.5258.00
3D probe positioner	R&S®RT-ZAP	1326.3641.02
Extended cable set for R&S®RT-ZVC, PCB probing, 1 current and voltage lead, length: 32 cm	R&S®RT-ZA30	1333.1686.02
Extended cable set for R&S®RT-ZVC, 4 mm probing, 1 current and voltage lead, length: 32 cm	R&S®RT-ZA31	1333.1692.02
Oscilloscope interface cable for R&S®RT-ZVC (included in R&S®RT-ZVC02/-ZVC04, 1326.0259.02/.04)	R&S®RT-ZA33	1333.1770.02
Extended cable set for R&S®RT-ZVC, 4 mm probing, 1 current and voltage lead, length: 1 m	R&S®RT-ZA34	1333.1892.02
Extended cable set for R&S®RT-ZVC, PCB probing, 1 current and voltage lead, length: 1 m	R&S®RT-ZA35	1333.1905.02
Solder-in cable set for R&S®RT-ZVC, 4 current and voltage solder-in cables, solder-in pins	R&S®RT-ZA36	1333.1911.02
Extended cable set for R&S®RT-ZVC, BNC connector, 1 current and voltage lead, length: 16 cm	R&S®RT-ZA37	1337.9130.02
Accessories		
Precision BNC to SMA adapter	R&S®RT-ZA16	1320.7074.02
Front cover, for R&S®RTP oscilloscopes	R&S®RTP-Z1	1337.9569.02
Front handles, for R&S®RTP oscilloscopes	R&S®RTP-B20	1338.0688.02
Transit case, for R&S®RTP oscilloscopes	R&S®RTP-Z4	1337.9575.02
Travel hard case, for R&S®RTP oscilloscopes and accessories	R&S®RTP-Z6	1338.0865.02
USB 2.0 compliance test fixture set	R&S®RT-ZF1	1317.3420.02
Ethernet compliance test fixture set	R&S®RT-ZF2	1317.5522.02
Frequency converter (100BASE-T1)	R&S®RT-ZF3	5025.0670.02
Ethernet 10BASE-Te fixture	R&S®RT-ZF4	1333.0915.02
Ethernet probe fixture	R&S®RT-ZF5	1333.0938.02
Frequency converter (1000BASE-T1)	R&S®RT-ZF6	1337.8579.02
Probe deskew and calibration test fixture	R&S®RT-ZF20	1800.0004.02
19" rackmount kit, for R&S®RTP oscilloscopes with 6 HU	R&S®ZZA-KN6	1175.3056.00

Warranty		
Base unit		3 years
All other items [10]		1 year
Options		
Extended warranty, one year	R&S®WE1	Please contact your local Rohde & Schwarz sales office.
Extended warranty, two years	R&S®WE2	
Extended warranty with calibration coverage, one year	R&S®CW1	
Extended warranty with calibration coverage, two years	R&S®CW2	
Extended warranty with accredited calibration coverage, one year	R&S®AW1	
Extended warranty with accredited calibration coverage, two years	R&S®AW2	

Extended warranty with a term of one and two years (WE1 and WE2)
Repairs carried out during the contract term are free of charge [11]. Necessary calibration and adjustments carried out during repairs are also covered.

Extended warranty with calibration coverage (CW1 and CW2)
Enhance your extended warranty by adding calibration coverage at a package price. This package ensures that your Rohde & Schwarz product is regularly calibrated, inspected and maintained during the term of the contract. It includes all repairs [11] and calibration at the recommended intervals as well as any calibration carried out during repairs or option upgrades.

Extended warranty with accredited calibration (AW1 and AW2)
Enhance your extended warranty by adding accredited calibration coverage at a package price. This package ensures that your Rohde & Schwarz product is regularly calibrated under accreditation, inspected and maintained during the term of the contract. It includes all repairs [11] and accredited calibration at the recommended intervals as well as any accredited calibration carried out during repairs or option upgrades.

[10] For options that are installed, the remaining base unit warranty applies if longer than 1 year. Exception: all batteries have a 1 year warranty.

[11] Excluding defects caused by incorrect operation or handling and force majeure. Wear-and-tear parts are not included.

Service that adds value

- Worldwide
- Local and personalized
- Customized and flexible
- Uncompromising quality
- Long-term dependability

Rohde&Schwarz

The Rohde&Schwarz electronics group offers innovative solutions in the following business fields: test and measurement, broadcast and media, secure communications, cybersecurity, monitoring and network testing. Founded more than 80 years ago, the independent company which is headquartered in Munich, Germany, has an extensive sales and service network with locations in more than 70 countries.

www.rohde-schwarz.com

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- Environmental compatibility and eco-footprint
- Energy efficiency and low emissions
- Longevity and optimized total cost of ownership

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ISO 9001

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Rohde&Schwarz training

www.training.rohde-schwarz.com

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